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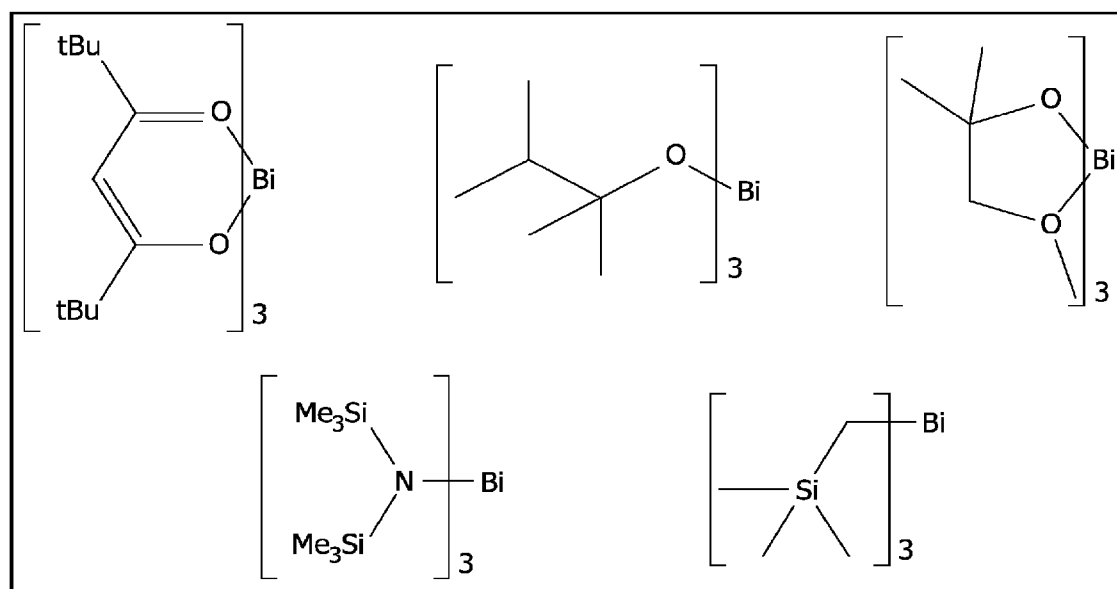
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(54) Title: PRECURSORS FOR DEPOSITION OF BISMUTH-CONTAINING FILMS



Conventional Art

FIG. 1

(57) **Abstract:** The disclosed and claimed subject matter relates to bismuth precursors of the formula $\text{Bi}(\text{Ra})_x(\text{Ar})_{3-x}$ where $x = 1$ or 2 and the use thereof as precursors for deposition of metal-containing films.

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PRECURSORS FOR DEPOSITION OF BISMUTH-CONTAINING FILMS

BACKGROUND

[0001] Field

[0002] The disclosed and claimed subject matter relates to bismuth precursors of the formula $\text{Bi}(\text{R}^a)_x(\text{Ar})_{3-x}$ where $x = 1$ or 2 and the use thereof as precursors for deposition of bismuth-containing films.

[0003] Related Art

[0004] Metal-containing films are used in semiconductor and electronics applications. Chemical Vapor Deposition (CVD) and Atomic Layer Deposition (ALD) have been applied as the main deposition techniques for producing thin films for semiconductor devices. These methods enable the achievement of conformal films (metal, metal oxide, metal nitride, metal silicide, and the like) through chemical reactions of metal-containing compounds (precursors). The chemical reactions occur on surfaces which may include metals, metal oxides, metal nitrides, metal silicides, and other surfaces. In CVD and ALD, the precursor molecule plays a critical role in achieving high quality films with high conformality and low impurities. The temperature of the substrate in CVD and ALD processes is an important consideration in selecting a precursor molecule. Higher substrate temperatures, in the range of 150 to 500 degrees Celsius ($^{\circ}\text{C}$), promote a higher film growth rate. The preferred precursor molecules must be stable in this temperature range. The preferred precursor is capable of being delivered to the reaction vessel in a liquid phase. Liquid phase delivery of precursors generally provides a more uniform delivery of the precursor to the reaction vessel than solid phase precursors.

[0005] CVD and ALD processes are increasingly used as they have the advantages of enhanced compositional control, high film uniformity, and effective control of doping. Moreover, CVD and ALD processes provide excellent conformal step coverage on highly non-planar geometries associated with modern microelectronic devices.

[0006] CVD is a chemical process whereby precursors are used to form a thin film on a substrate surface. In a typical CVD process, the precursors are passed over the surface of a substrate (*e.g.*, a wafer) in a low pressure or ambient pressure reaction chamber. The precursors react and/or decompose on the substrate surface creating a thin film of deposited material. Plasma can be used to assist in reaction of a precursor or for improvement of material properties. Volatile

by-products are removed by gas flow through the reaction chamber. The deposited film thickness can be difficult to control because it depends on coordination of many parameters such as temperature, pressure, gas flow volumes and uniformity, chemical depletion effects, and time.

[0007] ALD is a chemical method for the deposition of thin films. It is a self-limiting, sequential, unique film growth technique based on surface reactions that can provide precise thickness control and deposit conformal thin films of materials provided by precursors onto surfaces substrates of varying compositions. In ALD, the precursors are separated during the reaction. The first precursor is passed over the substrate surface producing a monolayer on the substrate surface. Any excess unreacted precursor is pumped out of the reaction chamber. A second precursor or co-reactant is then passed over the substrate surface and reacts with the first precursor, forming a second monolayer of film over the first-formed monolayer of film on the substrate surface. Plasma may be used to assist with reaction of a precursor or co-reactant or for improvement in materials quality. This cycle is repeated to create a film of desired thickness.

[0008] Thin films, and in particular thin metal-containing films, have a variety of important applications, such as in nanotechnology and the fabrication of semiconductor devices. Examples of such applications include capacitor electrodes, gate electrodes, adhesive diffusion barriers and integrated circuits.

[0009] Trimethyl bismuth (BiMe_3) and triphenyl bismuth (BiPh_3) are volatile, homoleptic bismuth compounds with some degree of utility as ALD precursors. Despite this, they are not practical options for ALD applications. Among other things, trimethyl bismuth is difficult to purify and deliver in a safe manner. *See Adv. Mater. Opt. Electron.*, 10, 193 (2000); *Integr. Ferroelectr.*, 45, 215 (2002). Trimethyl bismuth is also a pyrophoric liquid that has been stabilized with dioxane to prevent explosion when used as a bismuth source in MOCVD applications. While trimethyl bismuth and triethylbismuth were used for MOCVD applications, there are not practical options for atomic layer deposition due to very low thermal stability. *See Chem. Vap. Deposition*, 19, 61-67 (2013). While triphenyl bismuth has good thermal stability and it was used for atomic layer deposition, triphenyl bismuth is a solid with very low vapor pressure. *See Thin Solid Films*, 622, 65-70 (2017) and *Chem. Vap. Deposition*, 6, 139-145 (2000). These disadvantages are problematic for high volume manufacturing of semiconductor devices and therefore preclude their use in applications that require a high degree of control over conformality and precursor flux.

[0010] Aside from homoleptic alkyl and aryl compounds for consideration as bismuth precursors, other bismuth compounds are known for use in ALD in a limited capacity as illustrated in FIG. 1. See *Coord. Chem. Rev.*, 251, 974-1006 (2007); *Coord. Chem. Rev.*, 257, 3297-3322 (2013); *Organomet. Chem.*, 42, 1-53 (2019). For example, bismuth tris(2,2,6,6-tetramethyl-3,5-heptanedionate) has a high molecular weight and requires a high source temperature for precursor delivery. This precursor has a narrow ALD window of 275-300 °C. At lower deposition temperatures precursor condensation was observed while at higher temperatures the growth rate per cycle diminished. See *J. Phys. Chem. C*, 116, 3449-3456 (2012)).

[0011] Bismuth alkoxides compounds are relatively easy to prepare and are volatile. ALD of Bi₂O₃ employing a bismuth alkoxide precursor was demonstrated on substrates heated below 200 °C. However, at temperatures above 200 °C, and specifically closer to 300 °C, it is unlikely that bismuth alkoxides would be suitable for ALD of Bi₂O₃ due to a high rate of thermal decomposition. See *J. Vac. Sci. Technol. A.*, 32(1), 01A113 (2014).

[0012] Bismuth compounds containing silicon are problematic for ozone-ALD processes. It has been shown that the precursors tris(hexamethyldisilazane)bismuth and tris(trimethylsilylmethyl)bismuth deposit bismuth silicate thin films in ozone-based ALD. See *Chem. Vap. Deposition*, 11, 362-367 (2005).

[0013] Uses of bismuth compounds are also described in: *Thin Solid Films*, 622, 65-70 (2017); U.S. Patent No. 5,902,639; U.S. Patent No. 7,618,681; U.S. Patent No. 6,916,944; U.S. Patent No. 10,186,570; and U.S. Patent Application Publication No. 2010/0279011. None of these or the above references describe viable ALD of Bi₂O₃ by via processes employing heteroleptic bismuth precursors with aryl and alkyl precursors as disclosed and claimed herein.

SUMMARY

[0014] The disclosed and claimed subject matter relates to bismuth precursors of the formula Bi(R^a)_x(Ar)_{3-x} where x = 1 or 2 and the use thereof as precursors for deposition of bismuth oxide thin films under high through-put process parameters. Additionally, the process parameters are compatible with current state of the art methods for depositing high quality metal oxide thin films in semiconductor manufacturing. Therefore, mixed metal oxide thin films are achievable with the invented method and compositions. When two or more processes are compatible, both processes can be run consecutively on a single piece of equipment without requiring downtime to switch between parameters (e.g., changing the substrate temperature). High through-put process parameters for atomic layer deposition

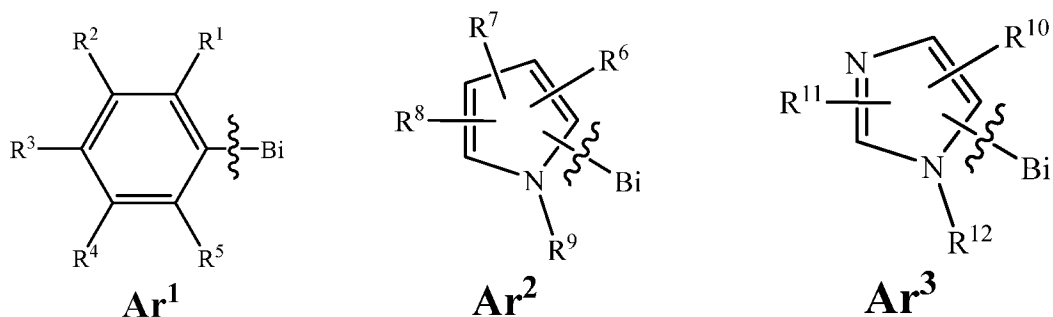
target a short cycle time. The precursor compositions of this invention enable high precursor flux, short precursor purge times, self-limiting growth behavior at substrate temperatures between about 200 °C and about 400 °C and, in some embodiments, the use of ozone as the second precursor.

[0015] In one embodiment, the disclosed and claimed subject matter pertains to heteroleptic bismuth compounds of the formula $\text{Bi}(\text{R}^a)_x(\text{Ar})_{3-x}$ where

- (i) $x = 1$ or 2 ,
- (ii) each R^a is independently one of an unsubstituted linear $\text{C}_1\text{-C}_6$ alkyl group, a linear $\text{C}_1\text{-C}_6$ alkyl group substituted with one or more halogen, a linear $\text{C}_1\text{-C}_6$ alkyl group substituted with an amino group, an unsubstituted branched $\text{C}_3\text{-C}_6$ alkyl group, a branched $\text{C}_3\text{-C}_6$ alkyl group substituted with one or more halogen, a branched $\text{C}_3\text{-C}_6$ alkyl group substituted with an amino group, an unsubstituted amine, a substituted amine, and $-\text{Si}(\text{CH}_3)_3$ and
- (iii) each Ar is independently one of a $\text{C}_3\text{-C}_8$ unsubstituted aromatic group, a $\text{C}_3\text{-C}_8$ aromatic group substituted with one or more halogen, a $\text{C}_3\text{-C}_8$ aromatic group substituted with an amino group, a 5-member heterocyclic ring and 6-member heterocyclic ring.

It has been shown that bismuth compounds so formulated have advantageous thermal stability and vapor pressure for atomic layer deposition processes in the manufacturing of semiconductor devices.

[0016] In one aspect of the above embodiment, each Ar is independently one of:



where each of $\text{R}^1\text{-R}^{12}$ is independently H or R^a . In a more specific embodiment, each of $\text{R}^1\text{-R}^{12}$ is independently H, an unsubstituted linear $\text{C}_1\text{-C}_6$ alkyl group and an unsubstituted branched $\text{C}_3\text{-C}_6$ alkyl group.

[0017] In another embodiment, the disclosed and claimed subject matter includes the use of the above-described heteroleptic bismuth compounds in ALD deposition processes.

BRIEF DESCRIPTION OF THE DRAWINGS

[0018] The accompanying drawings, which are included to provide a further understanding of the disclosed subject matter and are incorporated in and constitute a part of this specification, illustrate embodiments of the disclosed subject matter and together with the description serve to explain the principles of the disclosed subject matter. In the drawings:

[0019] FIG. 1 illustrates conventional art ALD bismuth precursors for depositing bismuth oxide containing thin films;

[0020] FIG. 2 illustrates the differential scanning calorimetry of BiMe_3 , BiPh_2Me , and BiPh_3 and compared their respective onsets of thermal decomposition;

[0021] FIG. 3 illustrates the vapor pressure curves of heteroleptic bismuth precursors (including vapor pressure curves for homoleptic precursors BiMe_3 and BiPh_3 for comparison);

[0022] FIG. 4 illustrates the growth rates of Bi_2O_3 thin films using heteroleptic and homoleptic bismuth precursors at various pulse times. Heteroleptic precursors showed better saturation behavior indicative of ALD mechanism; and

[0023] FIG. 5 illustrates the dependence of bismuth oxide thickness on the number of ALD cycles and that self-limited growth can be accomplished.

DETAILED DESCRIPTION

[0024] All references, including publications, patent applications, and patents, cited herein are hereby incorporated by reference to the same extent as if each reference were individually and specifically indicated to be incorporated by reference and were set forth in its entirety herein.

[0025] The use of the terms "a" and "an" and "the" and similar referents in the context of describing the disclosed and claimed subject matter (especially in the context of the following claims) are to be construed to cover both the singular and the plural, unless otherwise indicated herein or clearly contradicted by context. The terms "comprising," "having," "including," and "containing" are to be construed as open-ended terms (*i.e.*, meaning "including, but not limited to,") unless otherwise noted. Recitation of ranges of values herein are merely intended to serve as a shorthand method of referring individually to each separate value falling within the range, unless otherwise indicated herein, and each separate value is incorporated into the specification as if it were individually recited herein. All methods described herein can be performed in any suitable order unless otherwise indicated herein or otherwise clearly contradicted by context. The use of any and all examples, or exemplary language (*e.g.*, "such as") provided herein, is intended merely to better

illuminate the disclosed and claimed subject matter and does not pose a limitation on the scope of the disclosed and claimed subject matter unless otherwise claimed. No language in the specification should be construed as indicating any non-claimed element as essential to the practice of the disclosed and claimed subject matter. The use of the term “comprising” or “including” in the specification and the claims includes the narrower language of “consisting essentially of” and “consisting of.”

[0026] Embodiments of the disclosed and claimed subject matter are described herein, including the best mode known to the inventors for carrying out the disclosed and claimed subject matter. Variations of those embodiments may become apparent to those of ordinary skill in the art upon reading the foregoing description. The inventors expect skilled artisans to employ such variations as appropriate, and the inventors intend for the disclosed and claimed subject matter to be practiced otherwise than as specifically described herein. Accordingly, the disclosed and claimed subject matter includes all modifications and equivalents of the subject matter recited in the claims appended hereto as permitted by applicable law. Moreover, any combination of the above-described elements in all possible variations thereof is encompassed by the disclosed and claimed subject matter unless otherwise indicated herein or otherwise clearly contradicted by context.

[0027] For ease of reference, “microelectronic device” or “semiconductor device” corresponds to semiconductor wafers having integrated circuits, memory, and other electronic structures fabricated thereon, and flat panel displays, phase change memory devices, solar panels and other products including solar substrates, photovoltaics, and microelectromechanical systems (MEMS), manufactured for use in microelectronic, integrated circuit, or computer chip applications. Solar substrates include, but are not limited to, silicon, amorphous silicon, polycrystalline silicon, monocrystalline silicon, CdTe, copper indium selenide, copper indium sulfide, and gallium arsenide on gallium. The solar substrates may be doped or undoped. It is to be understood that the term “microelectronic device” or “semiconductor device” is not meant to be limiting in any way and includes any substrate that will eventually become a microelectronic device or microelectronic assembly.

[0028] As defined herein, the term “barrier material” corresponds to any material used in the art to seal the metal lines, *e.g.*, copper interconnects, to minimize the diffusion of said metal, *e.g.*, copper, into the dielectric material. Preferred barrier layer materials include tantalum, titanium, ruthenium, hafnium, and other refractory metals and their nitrides and silicides.

[0029] “Substantially free” is defined herein as less than 0.001 wt. %. “Substantially free” also includes 0.000 wt. %. The term “free of” means 0.000 wt. %. As used herein, “about” or “approximately” are intended to correspond to within $\pm 5\%$ of the stated value.

[0030] In all such compositions, wherein specific components of the composition are discussed in reference to weight percentage (or “weight %”) ranges including a zero lower limit, it will be understood that such components may be present or absent in various specific embodiments of the composition, and that in instances where such components are present, they may be present at concentrations as low as 0.001 weight percent, based on the total weight of the composition in which such components are employed. Note all percentages of the components are weight percentages and are based on the total weight of the composition, that is, 100%. Any reference to “one or more” or “at least one” includes “two or more” and “three or more” and so on.

[0031] Where applicable, all weight percents unless otherwise indicated are “neat” meaning that they do not include the aqueous solution in which they are present when added to the composition. For example, “neat” refers to the weight % amount of an undiluted acid or other material (*i.e.*, the inclusion 100 g of 85% phosphoric acid constitutes 85 g of the acid and 15 grams of diluent).

[0032] Moreover, when referring to the compositions described herein in terms of weight %, it is understood that in no event shall the weight % of all components, including non-essential components, such as impurities, add to more than 100 weight %. In compositions “consisting essentially of” recited components, such components may add up to 100 weight % of the composition or may add up to less than 100 weight %. Where the components add up to less than 100 weight %, such composition may include some small amounts of a non-essential contaminants or impurities. For example, in one such embodiment, the formulation can contain 2% by weight or less of impurities. In another embodiment, the formulation can contain 1% by weight or less than of impurities. In a further embodiment, the formulation can contain 0.05% by weight or less than of impurities. In other such embodiments, the constituents can form at least 90 wt%, more preferably at least 95 wt%, more preferably at least 99 wt%, more preferably at least 99.5 wt%, most preferably at least 99.9 wt%, of the composition, and can include other ingredients that do not material affect the performance of the composition. Otherwise, if no significant non-essential impurity component is present, it is understood that the composition of all essential constituent components will essentially add up to 100 weight %.

[0033] The headings employed herein are not intended to be limiting; rather, they are included for organizational purposes only.

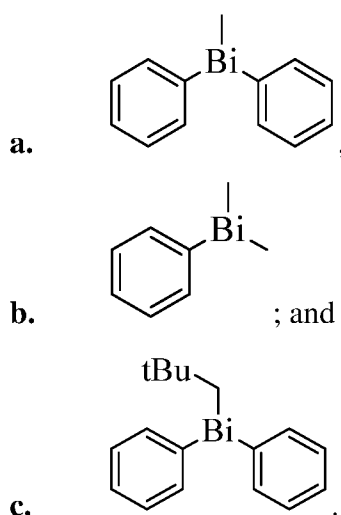
[0034] **Exemplary Embodiments**

[0035] As noted above, the disclosed and claimed subject matter pertains to heteroleptic bismuth compounds for use as ALD precursors.

[0036] **Disclosed and Claimed Heteroleptic Bismuth Precursors**

[0037] In one embodiment, the disclosed and claimed subject matter pertains to heteroleptic bismuth compounds of the formula $\text{Bi}(\text{R}^a)_x(\text{Ar})_{3-x}$ where

- (i) $x = 1$ or 2 ,
- (ii) each R^a is independently one of an unsubstituted linear $\text{C}_1\text{-C}_6$ alkyl group, a linear $\text{C}_1\text{-C}_6$ alkyl group substituted with one or more halogen, a linear $\text{C}_1\text{-C}_6$ alkyl group substituted with an amino group, an unsubstituted branched $\text{C}_3\text{-C}_6$ alkyl group, a branched $\text{C}_3\text{-C}_6$ alkyl group substituted with one or more halogen, a branched $\text{C}_3\text{-C}_6$ alkyl group substituted with an amino group, an unsubstituted amine, a substituted amine, and $-\text{Si}(\text{CH}_3)_3$ and
- (iii) each Ar is independently one of a $\text{C}_3\text{-C}_8$ unsubstituted aromatic group, a $\text{C}_3\text{-C}_8$ aromatic group substituted with one or more halogen, a $\text{C}_3\text{-C}_8$ aromatic group substituted with an amino group, a 5-member heterocyclic ring and 6-member heterocyclic ring and
- (iv) the precursor does not include:



It has been shown that bismuth compounds so formulated have advantageous thermal stability and vapor pressure for atomic layer deposition processes in the manufacturing of semiconductor devices.

[0038] R^a Alkyl Substituents

[0039] As noted above, each R^a is independently one of an unsubstituted linear C₁-C₆ alkyl group, a linear C₁-C₆ alkyl group substituted with one or more halogen, a linear C₁-C₆ alkyl group substituted with an amino group, an unsubstituted branched C₃-C₆ alkyl group, a branched C₃-C₆ alkyl group substituted with one or more halogen, a branched C₃-C₆ alkyl group substituted with an amino group, an unsubstituted amine, a substituted amine, and -Si(CH₃)₃.

[0040] In one embodiment, R^a is an unsubstituted linear C₁-C₆ alkyl group. In one aspect of this embodiment, R^a is a methyl group. In one aspect of this embodiment, R^a is an ethyl group. In one aspect of this embodiment, R^a is a propyl group. In one aspect of this embodiment, R^a is a butyl group. In one aspect of this embodiment, R^a is a pentyl group. In one aspect of this embodiment, R^a is a hexyl group.

[0041] In one embodiment, R^a is a substituted linear C₁-C₆ alkyl group substituted with one or more halogen. In one aspect of this embodiment, R^a is a methyl group substituted with one or more halogen. In one aspect of this embodiment, R^a is an ethyl group substituted with one or more halogen. In one aspect of this embodiment, R^a is a propyl group substituted with one or more halogen. In one aspect of this embodiment, R^a is a butyl group substituted with one or more halogen. In one aspect of this embodiment, R^a is a pentyl group substituted with one or more halogen. In one aspect of this embodiment, R^a is a hexyl group substituted with one or more halogen. In one aspect of this embodiment, the one or more halogen includes fluorine. In one aspect of this embodiment, the one or more halogen includes chlorine. In one aspect of this embodiment, the one or more halogen includes bromine. In one aspect of this embodiment, the one or more halogen includes iodine.

[0042] In one embodiment, R^a is a substituted linear C₁-C₆ alkyl group substituted with an amino group. In one aspect of this embodiment, R^a is a methyl group substituted with an amino group. In one aspect of this embodiment, R^a is an ethyl group substituted with an amino group. In one aspect of this embodiment, R^a is a propyl group substituted with an amino group. In one aspect of this embodiment, R^a is a butyl group substituted with an amino group. In one aspect of this embodiment, R^a is a pentyl group substituted with an amino group. In one aspect of this embodiment, R^a is a hexyl group substituted with an amino group.

[0043] In one embodiment, R^a is an unsubstituted branched C₃-C₆ alkyl group. In one aspect of this embodiment, R^a is an iso-propyl group. In one aspect of this embodiment, R^a is an

iso-butyl group. In one aspect of this embodiment, R^a is a sec-butyl group. In one aspect of this embodiment, R^a is a tert-butyl group. In one aspect of this embodiment, R^a is a branched pentyl group for example neo-pentyl, sec-pentyl or tert-pentyl. In one aspect of this embodiment, R^a is a neopentyl group. In one aspect of this embodiment, R^a is a branched hexyl group.

[0044] In one embodiment, R^a is a substituted branched C₃-C₆ alkyl group substituted with one or more halogen. In one aspect of this embodiment, R^a is an iso-propyl group substituted with one or more halogen. In one aspect of this embodiment, R^a is an iso-butyl group substituted with one or more halogen. In one aspect of this embodiment, R^a is a sec-butyl group substituted with one or more halogen. In one aspect of this embodiment, R^a is a tert-butyl group substituted with one or more halogen. In one aspect of this embodiment, R^a is a branched pentyl group substituted with one or more halogen. In one aspect of this embodiment, R^a is a neopentyl group substituted with one or more halogen. In one aspect of this embodiment, R^a is a branched hexyl group substituted with one or more halogen. In one aspect of this embodiment, the with one or more halogen includes fluorine. In one aspect of this embodiment, the with one or more halogen includes chlorine. In one aspect of this embodiment, the with one or more halogen includes bromine. In one aspect of this embodiment, the with one or more halogen includes iodine.

[0045] In one embodiment, R^a is a substituted branched C₃-C₆ alkyl group substituted with an amino group. In one aspect of this embodiment, R^a is an iso-propyl group substituted with an amino group. In one aspect of this embodiment, R^a is an iso-butyl group substituted with an amino group. In one aspect of this embodiment, R^a is a sec-butyl group substituted with an amino group. In one aspect of this embodiment, R^a is a tert-butyl group substituted with an amino group. In one aspect of this embodiment, R^a is a branched pentyl group substituted with an amino group. In one aspect of this embodiment, R^a is a neopentyl group substituted with an amino group. In one aspect of this embodiment, R^a is a branched hexyl group substituted with an amino group.

[0046] In one embodiment, R^a is an unsubstituted amine.

[0047] In one embodiment, R^a is a substituted amine.

[0048] In one embodiment, R^a is -Si(CH₃)₃.

[0049] In some embodiments, the R^a has a structure described in Table 1:

Linear alkyl	Secondary alkyl	Tertiary
Methyl	Iso-propyl	tert-butyl
Ethyl	Iso-butyl	tert-pentyl
Propyl	Iso-pentyl	
n-Butyl	Sec-butyl	
n-pentyl	Sec-pentyl	

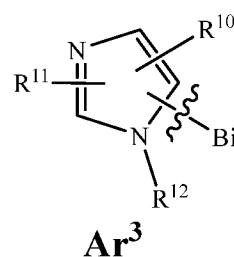
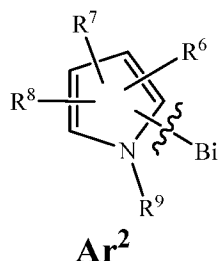
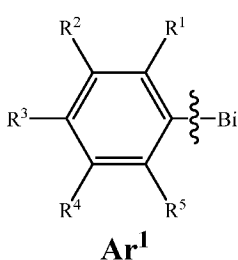
Table 1

[0050] The R^a substituents are not limited to those exemplified in Table 1.

[0051] **Ar Substituents**

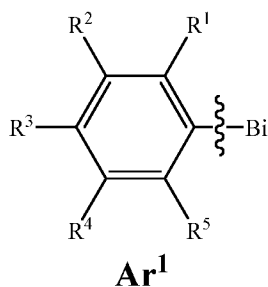
[0052] As noted above, each Ar is independently one of a C_3 - C_8 unsubstituted aromatic group, a C_3 - C_8 aromatic group substituted with one or more halogen, a C_3 - C_8 aromatic group substituted with an amino group, a 5-member heterocyclic ring and 6-member heterocyclic ring.

[0053] In one embodiment, each Ar is independently one of:



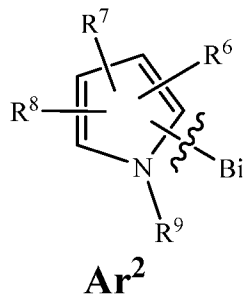
where each of R^1 - R^{12} is independently H or R^a . In a more specific embodiment, each of R^1 - R^{12} is independently H. In a more specific embodiment, each of R^1 - R^{12} is independently R^a . In a more specific embodiment, each of R^1 - R^{12} is independently the same R^a . In a more specific embodiment, each of R^1 - R^{12} is an unsubstituted linear C_1 - C_6 alkyl group. In a more specific embodiment, each of R^1 - R^{12} is an unsubstituted branched C_3 - C_6 alkyl group.

[0054] In one embodiment, each Ar is:



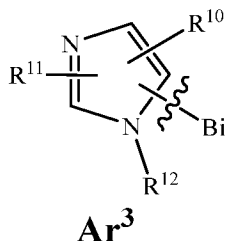
where each of R^1 - R^5 is independently H or R^a . In a more specific embodiment, each of R^1 - R^5 is independently H. In a more specific embodiment, each of R^1 - R^5 is independently R^a . In a more specific embodiment, each of R^1 - R^5 is independently the same R^a . In a more specific embodiment, each of R^1 - R^5 is an unsubstituted linear C_1 - C_6 alkyl group. In a more specific embodiment, each of R^1 - R^5 is an unsubstituted branched C_3 - C_6 alkyl group.

[0055] In one embodiment, each Ar is:



where each of R^6 - R^9 is independently H or R^a . In a more specific embodiment, each of R^6 - R^9 is independently H. In a more specific embodiment, each of R^6 - R^9 is independently R^a . In a more specific embodiment, each of R^6 - R^9 is independently the same R^a . In a more specific embodiment, each of R^6 - R^9 is an unsubstituted linear C_1 - C_6 alkyl group. In a more specific embodiment, each of R^6 - R^9 is an unsubstituted branched C_3 - C_6 alkyl group.

[0056] In one embodiment, each Ar is:



where each of R^{10} - R^{12} is independently H or R^a . In a more specific embodiment, each of R^{10} - R^{12} is independently H. In a more specific embodiment, each of R^{10} - R^{12} is independently R^a . In a more specific embodiment, each of R^{10} - R^{12} is independently the same R^a . In a more specific embodiment, each of R^{10} - R^{12} is an unsubstituted linear C_1 - C_6 alkyl group. In a more specific embodiment, each of R^{10} - R^{12} is an unsubstituted branched C_3 - C_6 alkyl group.

[0057] In some embodiments, the Ar has a structure as illustrated in Table 2:

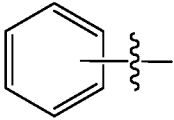
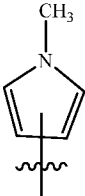
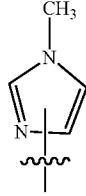
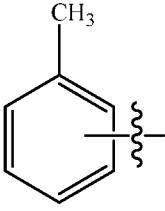
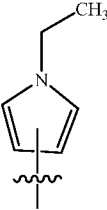
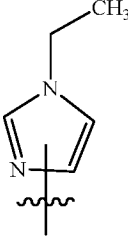
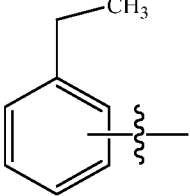
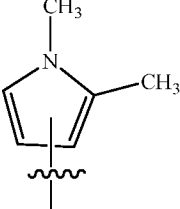
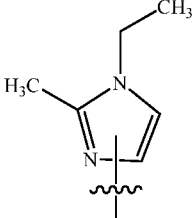
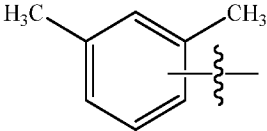
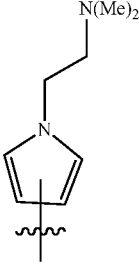
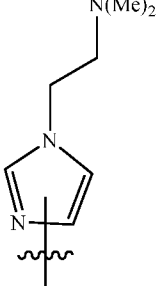
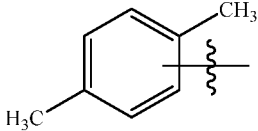
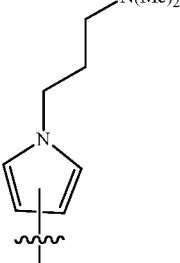
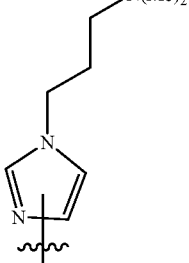
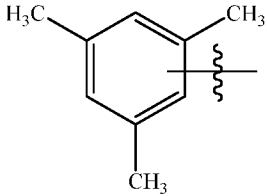
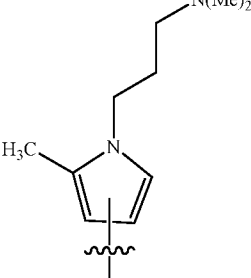
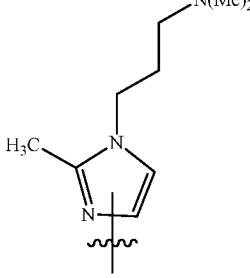
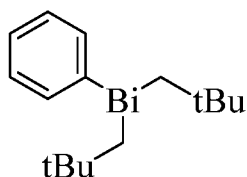
Aryl – Ar ¹	Pyrrolyl – Ar ²	Imidazolyl – Ar ³
		
		
		
		
		
		

Table 2

[0058] The Ar substituents are not limited to those exemplified in Table 2.

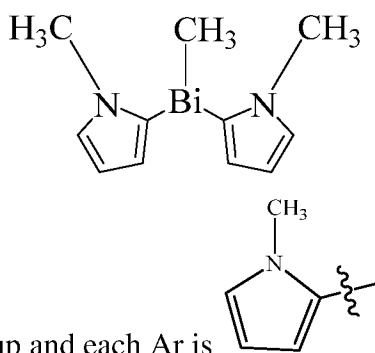
[0059] **Exemplary Heteroleptic Bismuth Precursors**

[0060] In one aspect of this embodiment, the heteroleptic bismuth compound is “BiPhNp₂” having the following structure:



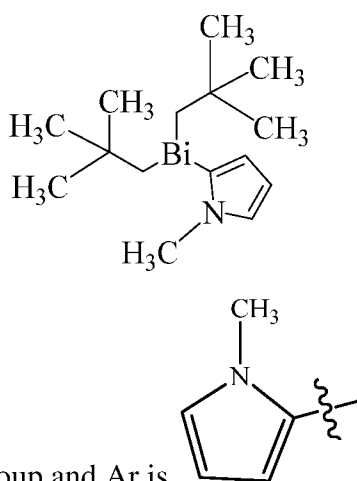
In this embodiment, in the formula Bi(R^a)_x(Ar)_{3-x}, x = 2, each R^a is a neo-pentyl group and Ar is a phenyl group.

[0061] In one aspect of this embodiment, the heteroleptic bismuth compound is “BiPyr₂Me” having the following structure:



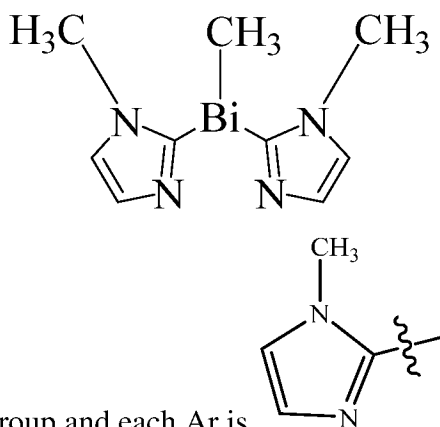
wherein x = 1, R^a is a methyl group and each Ar is

[0062] In one aspect of this embodiment, the heteroleptic bismuth compound is “BiPyrNp₂” having the following structure:



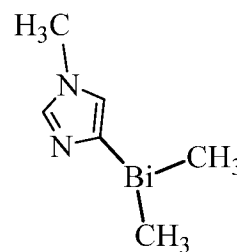
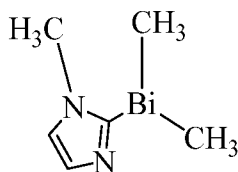
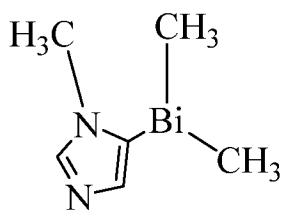
wherein x = 2, R^a is a neo-pentyl group and Ar is

[0063] In one aspect of this embodiment, the heteroleptic bismuth compound is “BiImid₂Me” having the following structure or the isomer of the following structure:



wherein $x = 1$, R^a is a methyl group and each Ar is

[0064] In one aspect of this embodiment, the heteroleptic bismuth compound is “BiImidMe₂” having one of the following structure or the isomers of the following structures:



[0065] Method of Use

[0066] The disclosed and claimed subject matter further includes the use of a heteroleptic bismuth compound of formula $\text{Bi}(\text{R}^a)_x(\text{Ar})_{3-x}$ where

- (i) $x = 1$ or 2 ,
- (ii) each R^a is independently one of an unsubstituted linear C_1 - C_6 alkyl group, a linear C_1 - C_6 alkyl group substituted with one or more halogen, a linear C_1 - C_6 alkyl group substituted with an amino group, an unsubstituted branched C_3 - C_6 alkyl group, a branched C_3 - C_6 alkyl group substituted with one or more halogen, a branched C_3 - C_6 alkyl group substituted with an amino group, an unsubstituted amine, a substituted amine, and $-\text{Si}(\text{CH}_3)_3$ and
- (iii) each Ar is independently one of a C_3 - C_8 unsubstituted aromatic group, a C_3 - C_8 aromatic group substituted with one or more halogen, a C_3 - C_8 aromatic group substituted with an amino group, a 5-member heterocyclic ring and 6-member heterocyclic ring

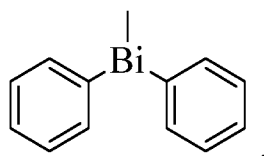
to deposit bismuth containing films using any chemical vapor deposition process known to those of skill in the art. As used herein, the term “chemical vapor deposition process” refers to any

process wherein a substrate is exposed to one or more volatile precursors, which react and/or decompose on the substrate surface to produce the desired deposition.

[0067] In one embodiment, the method includes the use of heteroleptic bismuth compound to deposit bismuth containing films using an atomic layer deposition process (ALD). As used herein, the term “atomic layer deposition process” or ALD refers to a self-limiting (*e.g.*, the amount of film material deposited in each reaction cycle is constant), sequential surface chemistry that deposits films of materials onto substrates of varying compositions. Although the precursors, reagents and sources used herein may be sometimes described as “gaseous,” it is understood that the precursors can be either liquid or solid which are transported with or without an inert gas into the reactor via direct vaporization, bubbling or sublimation. In some case, the vaporized precursors can pass through a plasma generator. The term “reactor” as used herein, includes without limitation, reaction chamber, reaction vessel or deposition chamber.

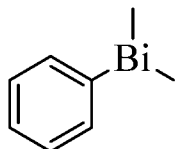
[0068] In one embodiment, the heteroleptic bismuth compound used in the disclosed and claimed methods to deposit bismuth containing films includes, consist essentially of or consists of the disclosed and claimed heteroleptic bismuth precursors $\text{Bi}(\text{R}^a)_x(\text{Ar})_{3-x}$ described above in the section “Disclosed and Claimed Heteroleptic Bismuth Precursors.” In one aspect of this embodiment, the heteroleptic bismuth precursor includes, consists essentially of or consists of BiPhNp_2 . In one aspect of this embodiment, the heteroleptic bismuth precursor includes, consists essentially of or consists of BiPyr_2Me . In one aspect of this embodiment, the heteroleptic bismuth precursor includes, consists essentially of or consists of BiPyrNp_2 . In one aspect of this embodiment, the heteroleptic bismuth precursor includes, consists essentially of or consists of BiImid_2Me . In one aspect of this embodiment, the heteroleptic bismuth precursor includes, consists essentially of or consists of BiImidMe_2 .

[0069] In another embodiment, the heteroleptic bismuth compound used in the disclosed and claimed methods to deposit bismuth containing films includes, consist essentially of or consists of having a heteroleptic bismuth precursor of formula $\text{Bi}(\text{R}^a)_x(\text{Ar})_{3-x}$ where $x = 1$, R^a is a methyl group and each Ar is a phenyl group (“ BiPh_2Me ”):



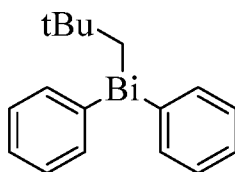
The precursor BiPh₂Me, but not its use in a deposition process, is described in *Organometallics*, 20(3), 586-589 (2001) and *Chem. Ber.*, 118, 1031-1038 (1985).

[0070] In another embodiment, the heteroleptic bismuth compound used in the disclosed and claimed methods to deposit bismuth containing films includes, consist essentially of or consists of having a heteroleptic bismuth precursor of formula Bi(R^a)_x(Ar)_{3-x} where x =2, each R^a is a methyl group and Ar is a phenyl group (“BiPhMe₂”):



The precursor BiPhMe₂, but not its use in a deposition process, is described in *Z. Naturforsch.*, B, 40, 1476 (1985).

[0071] In another embodiment, the heteroleptic bismuth compound used in the disclosed and claimed methods to deposit bismuth containing films includes, consist essentially of or consists of having a heteroleptic bismuth precursor of formula Bi(R^a)_x(Ar)_{3-x} where x =1, Ra is neo-pentyl group and each Ar is a phenyl group (“BiPh₂Np”):



The precursor BiPh₂Np, but not its use in a deposition process, is described in *Organometallics*, 22 (14), 2929-2924 (2003).

[0072] In another embodiment, the heteroleptic bismuth compound used in the disclosed and claimed methods to deposit bismuth containing films includes, consist essentially of or consists of having a heteroleptic bismuth precursor of formula Bi(R^a)_x(Ar)_{3-x} described above.

[0073] Chemical vapor deposition processes in which the disclosed and claimed precursors can be utilized include, but are not limited to, those used for the manufacture of semiconductor type microelectronic devices such as ALD and plasma enhanced ALD (PEALD). This, in one embodiment, for example, the metal-containing film is deposited using an ALD process. In another embodiment, for example, the metal-containing film is deposited using a plasma enhanced ALD (PEALD) process.

[0074] Suitable substrates on which the disclosed and claimed precursors can be deposited are not particularly limited and vary depending on the final use intended. For example, the substrate

may be chosen from oxides such as HfO₂ based materials, TiO₂ based materials, ZrO₂ based materials, rare earth oxide-based materials, ternary oxide-based materials, etc. or from nitride-based films. Other substrates may include solid substrates such as metal substrates (for example, Au, Pd, Rh, Ru, W, Al, Ni, Ti, Co, Pt and metal silicides (*e.g.*, TiSi₂, CoSi₂, and NiSi₂); metal nitride containing substrates (*e.g.*, TaN, TiN, WN, TaCN, TiCN, TaSiN, and TiSiN); semiconductor materials (*e.g.*, Si, SiGe, GaAs, InP, diamond, GaN, and SiC); insulators (*e.g.*, SiO₂, Si₃N₄, SiON, HfO₂, Ta₂O₅, ZrO₂, TiO₂, Al₂O₃, and barium strontium titanate); combinations thereof. Preferred substrates include HfO₂ based materials, TiO₂ based materials, ZrO₂ based materials, rare earth oxide-based materials, and silicon oxide-based substrates.

[0075] In such deposition methods and processes an oxidizing agent can be utilized. The oxidizing agent is typically introduced in gaseous form. Examples of suitable oxidizing agents include, but are not limited to, oxygen gas, water vapor, ozone, oxygen plasma, or mixtures thereof.

[0076] The deposition methods and processes may also involve one or more purge gases. The purge gas, which is used to purge away unconsumed reactants and/or reaction byproducts, is an inert gas that does not react with the precursors. Exemplary purge gases include, but are not limited to, argon (Ar), nitrogen (N₂), helium (He), neon, and mixtures thereof. For example, a purge gas such as Ar is supplied into the reactor at a flow rate ranging from about 10 to about 2000 sccm for about 0.1 to 10000 seconds, thereby purging the unreacted material and any byproduct that may remain in the reactor.

[0077] The deposition methods and processes require that energy be applied to the at least one of the precursors, oxidizing agent, other precursors or combination thereof to induce reaction and to form the metal-containing film or coating on the substrate. Such energy can be provided by, but not limited to, thermal, plasma, pulsed plasma, helicon plasma, high density plasma, inductively coupled plasma, X-ray, e-beam, photon, remote plasma methods, and combinations thereof. In some processes, a secondary RF frequency source can be used to modify the plasma characteristics at the substrate surface. When utilizing plasma, the plasma-generated process may include a direct plasma-generated process in which plasma is directly generated in the reactor, or alternatively a remote plasma-generated process in which plasma is generated outside of the reactor and supplied into the reactor.

[0078] When utilized in such deposition methods and processes suitable precursors—such as those presently disclosed and claimed—may be delivered to the reaction chamber such as an

ALD reactor in a variety of ways. In some instances, a liquid delivery system may be utilized. In other instances, a combined liquid delivery and flash vaporization process unit may be employed, such as, for example, the turbo vaporizer manufactured by MSP Corporation of Shoreview, MN, to enable low volatility materials to be volumetrically delivered, which leads to reproducible transport and deposition without thermal decomposition of the precursor. The precursor compositions described herein can be effectively used as source reagents via direct liquid injection (DLI) to provide a vapor stream of these metal precursors into an ALD reactor.

[0079] When used in these deposition methods and processes, the disclosed and claimed precursors can be combined with and include hydrocarbon solvents which are particularly desirable due to their ability to be dried to sub-ppm levels of water. Exemplary hydrocarbon solvents that can be used in the precursors include, but are not limited to, toluene, mesitylene, cumene (isopropylbenzene), p-cymene (4-isopropyl toluene), 1,3-diisopropylbenzene, octane, dodecane, 1,2,4-trimethylcyclohexane, n-butylcyclohexane, and decahydronaphthalene (decalin). The disclosed and claimed precursors can also be stored and used in stainless steel containers. In certain embodiments, the hydrocarbon solvent is a high boiling point solvent or has a boiling point of 100 degrees Celsius or greater. The disclosed and claimed precursors can also be mixed with other suitable metal precursors, and the mixture used to deliver both metals simultaneously for the growth of a binary metal-containing films.

[0080] A flow of argon and/or other gas may be employed as a carrier gas to help deliver a vapor containing at least one of the disclosed and claimed precursors to the reaction chamber during the precursor pulsing. When delivering the precursors, the reaction chamber process pressure is between 1 and 50 torr, preferably between 5 and 20 torr.

[0081] Substrate temperature can be an important process variable in the deposition of high-quality metal-containing films. Typical substrate temperatures range from about 150 °C to about 550 °C. Higher temperatures can promote higher film growth rates.

[0082] In view of the forgoing, those skilled in the art will recognize that the disclosed and claimed subject matter further includes the use of the disclosed and claimed precursors in chemical vapor deposition processes as follows.

[0083] In one embodiment, the disclosed and claimed subject matter includes a method for forming a bismuth-containing film on at least one surface of a substrate that includes the steps of:

- a. providing the substrate with the at least one surface in a reaction vessel;
- b. forming a bismuth-containing film on the at least one surface by a thermal atomic layer deposition (ALD) process using one or the disclosed and claimed precursors as a metal source compound for the deposition process.

In a further aspect of this embodiment, the method includes introducing at least one reactant into the reaction vessel. In a further aspect of this embodiment, the method includes introducing at least one reactant into the reaction vessel where the at least one reactant is selected from the group of water, diatomic oxygen, oxygen plasma, ozone, NO, N₂O, NO₂, carbon monoxide, carbon dioxide and combinations thereof. In another aspect of this embodiment, the method includes introducing at least one reactant into the reaction vessel where the at least one reactant is selected from the group of ammonia, hydrazine, monoalkylhydrazine, dialkylhydrazine, nitrogen, nitrogen/hydrogen, ammonia plasma, nitrogen plasma, nitrogen/hydrogen plasma, and combinations thereof. In another aspect of this embodiment, the method includes introducing at least one reactant into the reaction vessel where the at least one reactant is selected from the group hydrogen, hydrogen plasma, a mixture of hydrogen and helium, a mixture of hydrogen and argon, hydrogen/helium plasma, hydrogen/argon plasma, boron-containing compounds, silicon-containing compounds and combinations thereof.

[0084] In one embodiment, the disclosed and claimed subject matter includes a method of forming a bismuth-containing film via a thermal atomic layer deposition (ALD) process or thermal ALD-like process that includes the steps of:

- a. providing a substrate in a reaction vessel;
- b. introducing into the reaction vessel one or more of the disclosed and claimed precursors;
- c. purging the reaction vessel with a first purge gas;
- d. introducing into the reaction vessel a source gas;
- e. purging the reaction vessel with a second purge gas;
- f. sequentially repeating steps b through e until a desired thickness of the bismuth-containing film is obtained.

In a further aspect of this embodiment, the source gas is one or more of an oxygen-containing source gas selected from water, diatomic oxygen, ozone, NO, N₂O, NO₂, carbon monoxide, carbon dioxide and combinations thereof. In another aspect of this embodiment, the source gas is one or more of a nitrogen-containing source gas selected from ammonia, hydrazine, monoalkylhydrazine, dialkylhydrazine, nitrogen, nitrogen/hydrogen, ammonia plasma, nitrogen plasma, nitrogen/hydrogen plasma and mixture thereof. In a further aspect of this embodiment, the first and second purge gases are each independently selected from one or more of argon, nitrogen, helium, neon, and combinations thereof. In a further aspect of this embodiment, the method further includes applying energy to the one or more precursor, the source gas, the substrate, and combinations thereof, wherein the energy is one or more of thermal, plasma, pulsed plasma, helicon plasma, high density plasma, inductively coupled plasma, X-ray, e-beam, photon, remote plasma methods and combinations thereof. In a further aspect of this embodiment, step b of the method further includes introducing into the reaction vessel the precursor using a stream of carrier gas to deliver a vapor of the precursor into the reaction vessel. In a further aspect of this embodiment, step b of the method further includes use of a solvent medium comprising one or more of toluene, mesitylene, isopropylbenzene, 4-isopropyl toluene, 1,3-diisopropylbenzene, octane, dodecane, 1,2,4-trimethylcyclohexane, n-butylcyclohexane, and decahydronaphthalene and combinations thereof.

[0085] In one aspect of this disclosure the bismuth precursors may be used to co-deposit multi-component oxide films. Multi-component oxide film may further include an oxide of one or more elements selected from magnesium, calcium, strontium, barium, aluminum, gallium, indium, titanium, zirconium, hafnium, vanadium, niobium, tantalum, molybdenum, tungsten, tellurium and antimony.

[0086] In one embodiment, the disclosed and claimed subject matter includes a method of forming a bismuth-containing multi-component oxide film in a thermal atomic layer deposition (ALD) process or thermal ALD-like process that includes the steps of:

- a. providing a substrate in a reaction vessel;
- b. introducing into the reaction vessel one or more of the disclosed and claimed bismuth precursors;
- c. introducing into the reaction vessel one or more of the co-precursors including an element other than bismuth;
- d. purging the reaction vessel with a first purge gas;

- e. introducing into the reaction vessel a source gas;
- f. purging the reaction vessel with a second purge gas;
- g. sequentially repeating steps b through f until a desired thickness of the bismuth-containing multi-component oxide film is obtained.

[0087] In another embodiment, the disclosed and claimed subject matter includes a method of forming a bismuth-containing multi-component oxide film in a thermal atomic layer deposition (ALD) process or thermal ALD-like process that includes the steps of:

- a. providing a substrate in a reaction vessel;
- b. introducing into the reaction vessel one or more of the disclosed and claimed bismuth precursors;
- c. purging the reaction vessel with a first purge gas;
- d. introducing into the reaction vessel a source gas;
- e. purging the reaction vessel with a second purge gas;
- f. introducing into the reaction vessel one or more of the co-precursors comprising an element other than bismuth;
- g. purging the reaction vessel with a third purge gas;
- h. introducing into the reaction vessel a source gas;
- i. purging the reaction vessel with a fourth purge gas;
- j. sequentially repeating steps b through i until a desired thickness of the bismuth-containing multi-component oxide film is obtained.

[0088] The examples of the co-precursors include but are not limited to trimethylaluminum, tetrakis(dimethylamino) titanium, tetrakis(ethylmethylamino) zirconium, tetrakis(ethylmethylamino) hafnium and tris-isopropylcyclopentadienyl lanthanum.

[0089] In another embodiment bismuth-containing film is deposited directly on a substance that promotes self-limited growth, *i.e.*, an “SLG oxide layer.” An SLG oxide layer is a thin layer of oxide (also thin film of oxide) which stimulates self-limited growth of the bismuth-containing film. The self-limited growth occurs where and when the deposition rate of the bismuth-containing film substantially drops with increasing number of cycles. Self-limited growth is desired for conformal deposition of thin films on high aspect ratio features. Without being bound by theory it is believed that self-limited growth is due to significantly lower deposition rate of bismuth-containing film on bismuth-containing film compared to deposition rate of bismuth-containing film on SLG oxide layer.

[0090] The examples of SLG oxide may include but are not limited to aluminum oxide and titanium oxide. The thickness of SLG oxide layer is preferably < 5 nm, more preferably < 3 nm and more preferably < 1 nm.

[0091] **Examples**

[0092] Reference will now be made to more specific embodiments of the present disclosure and experimental results that provide support for such embodiments. The examples are given below to more fully illustrate the disclosed and claimed subject matter and should not be construed as limiting the disclosed subject matter in any way.

[0093] It will be apparent to those skilled in the art that various modifications and variations can be made in the disclosed subject matter and specific examples provided herein without departing from the spirit or scope of the disclosed subject matter. Thus, it is intended that the disclosed subject matter, including the descriptions provided by the following examples, covers the modifications and variations of the disclosed subject matter that come within the scope of any claims and their equivalents.

[0094] **Materials and Methods:**

[0095] All reactions and manipulations described in the examples were conducted under a nitrogen atmosphere using an inert atmosphere glove box or standard Schlenk techniques. All chemicals were received from Millipore-Sigma.

[0096] **Specific Examples**

[0097] **Example 1: Synthesis of BiPh₂Cl**

[0098] BiCl₃ (34.23 g) was dissolved in 100 mL of tetrahydrofuran. BiPh₃ (28.35 g), was dissolved in 200 mL of tetrahydrofuran. The solution of BiCl₃ in tetrahydrofuran was added dropwise to the solution of BiPh₃ at -10°C over 1.5 hours. The cloudy solution was stirred overnight at RT and filtered to remove a small amount of insoluble solid. The solvent was removed under vacuum to afford a white solid. The solid was dried under vacuum at 60°C for 1 hour, washed with diethyl ether, and re-dried. 34.2 g of BiPh₂Cl was collected, 98 %.

[0099] **Analysis:** ¹H NMR (C₆D₆, 25 °C): 7.35 (m, 4H), 7.62 (t, 4H), 8.29 (d, 2H)

[0100] **Example 2: Synthesis and Purification of BiPh₂Me**

[0101] Synthesis of BiPh₂Me is described in *Chem. Ber.*, 118, 1031-1038 (1985). Attempts to duplicate the procedure afforded a low purity material that was difficult to purify by vacuum distillation. Changing the reaction solvent to toluene afforded a pure material which could be purified

by vacuum distillation. In theory, the heterogeneous reaction mixture in toluene separated the product from insoluble impurities. The impurities, if soluble, would catalyze product decomposition.

[0102] BiPh₂Cl (34.23 g, 85.9 mmol) was suspended in 250 mL of toluene and cooled to -78 °C. MeLi (60 mL, 1.6M in Et₂O, 96 mmol) was added dropwise via a cannula and the mixture was stirred for 18h while warming to RT. All volatile components were removed under reduced pressure to yield a cloudy oil. The oil was extracted with portions of hexane (3 x 50 mL). Each portion of hexane was collected by filtration. The filtrates were combined and concentrated under reduced pressure to afford a colorless oil (30.42 g, 99 %). The oil was purified by fractional vacuum distillation. The first fraction was collected at 31°C/60mTorr as a colorless oil (3.5 g, confirmed by ¹H NMR as BiPhMe₂). The second, main fraction was collected at 98 °C / 77 mTorr (25.2 g, 78%).

[0103] **Analysis:** ¹H NMR (C₆D₆, 25 °C): 1.19 (s, 3H), 7.08-7.13 (m, 3H), 7.15-7.19 (m, 4H), 7.67-7.70 (m, 4H).

[0104] **Example 3: Synthesis of BiPh(Np)₂**

[0105] BiPhCl₂ (37.63 g, 105.4 mmol) was suspended in 300 mL of toluene and cooled to -78 °C. Neo-pentyl MgCl (209 mL, 1 M in THF, 209 mmol) was added dropwise via a cannula and the mixture was stirred for 18 h while warming to RT. A large amount of solid had formed after 18 h such that magnetic stirring was ineffective. 200 mL of THF was added to dissolve the solid. Stirring continued for 24 h. All volatile components were removed under reduced pressure to yield a light brown solid. The solid was extracted with portions of hexane (3 x 150 mL). Each portion of hexane was collected by filtration. The three hexane filtrates were combined and concentrated under reduced pressure the afford a colorless oil. The colorless oil was purified by vacuum distillation (41.22 g, 91.3%).

[0106] **Analysis:** ¹H NMR (C₆D₆, 25 °C): 1.02 (s, 18H), 2.15 (d, 2H), 2.27 (2, 2H), 7.13-7.17 (m, 1H), 7.19-7.24 (m, 2H), 7.81-7.84 (m, 2H).

[0107] **Example 4: Synthesis of BiPyr(Np)₂**

[0108] Synthesis of tris (N-methyl-2-pyrrolyl) bismuth (BiPyr₃) was synthesized via salt metathesis of bismuth trichloride and N-methyl-2-pyrrolyl lithium. Analytical data from *Dalton Trans.*, 46, 8269-8278 (2017) was used for comparison to confirm the synthesis.

[0109] BiPyr₃ (3.04 g, 6.77 mmol) dissolved in 50 mL of THF was added dropwise to BiCl₃ (4.27 g, 13.54 mmol) dissolved in 100 mL in THF. The solution was stirred for 18 h. While cooled to -78 °C, Neo-pentyl MgCl (40.6 mL, 1 M in THF, 40.6 mmol) was added dropwise via a cannula.

The mixture was stirred for 18 h while warming to RT. Volatile components were removed under a reduced pressure of 1 torr and mild heating of the flask to 30 °C. The crude material was extracted with portions of hexane (3 x 50 mL). Each portion of hexane was collected by filtration. The filtrates were combined and concentrated under reduced pressure to afford a cloudy oil (8.61 g, 98 %). The oil was heated to 70 °C at 60 mTorr to sublime out tris-neo-pentyl bismuth. The oil was then heated to 110 °C at 60 mTorr to distill a colorless liquid (2.17 g, 25 %, b.p. = 63 °C/60 mTorr).

[0110] Analysis: ^1H NMR (C_6D_6 , 25 °C): 1.01 (s, 18H), 2.20 (d, 2H), 2.49 (2, 2H), 3.23 (s, 3H), 6.52-6.55 (m, 2H), 6.65 (t, 1H).

[0111] Example 5: Synthesis of $\text{Bi}(\text{Np})_3$

[0112] BiCl_3 (46.52 g, 116 mmol) was dissolved in 200 mL of THF and cooled to -78 °C. Neo-pentyl MgCl (350 mL, 1 M in THF, 350 mmol) was added dropwise via a cannula and the mixture was stirred for 18 h while warming to RT. All volatile components were removed under reduced pressure (1 Torr, 30 °C) to yield a light grey solid. The solid was extracted with portions of pentane (4 x 200 mL). Each portion of pentane was collected by filtration, combined and then concentrated under reduced pressure (1 Torr) to afford a white solid. The solid was allowed to sublime out tris-neo-pentyl bismuth at 80 °C, 100 mTorr (48 g, 96%).

[0113] Analysis: ^1H NMR (C_6D_6 , 25 °C): 1.09 (s, 27H), 2.11 (d, 6H).

[0114] Example 6: Thermal analyses of heteroleptic bismuth precursors

[0115] Physical properties such as thermal stability and volatility are determined by the ligands in a precursor. Bismuth aryl compounds have low volatility and high thermal stability. Bismuth alkyl compounds have high volatility and low thermal stability. Heteroleptic bismuth precursors containing aryl and alkyl ligands, surprisingly, have intermediate physical properties with respect to the homoleptic compounds. Atomic layer deposition employing a heteroleptic bismuth precursor can deposit thin films of Bi_2O_3 without the limitations imposed by low volatility and low thermal stability. Heteroleptic bismuth precursors enables atomic layer deposition of Bi_2O_3 in a manner suitable with high volume manufacturing of semiconductor and memory devices.

[0116] FIG. 2 illustrates the thermal stability analysis of BiMe_3 , BiPh_2Me , and BiPh_3 measured and compared their respective onsets of thermal decomposition by differential scanning calorimetry. The trend in thermal stability was dependent on the types of ligands in the compound. As shown in Table 3, BiMe_3 began to decompose around 170 °C, BiPh_2Me around 250°C and

BiPh₃ decomposed at temperatures near 300 °C. Specifically, BiPh₂Me and BiPh₃ began to decompose at 250 °C and 300 °C, respectively.

Precursor	Decomposition Temperature	Temperature (at 1 Torr vapor pressure)
BiMe ₃	170 °C	< 20 °C
BiPh ₂ Me	250 °C	110 °C
BiPh ₃	300 °C	175 °C

Table 3

[0117] FIG. 3 illustrates the vapor pressure curves of heteroleptic bismuth precursors (including vapor pressure curves for homoleptic precursors BiMe₃ and BiPh₃ for comparison).

[0118] Evaporation data for several heteroleptic bismuth compounds were collected by TGA to determine the temperature required to produce 1 Torr of vapor pressure. As shown in Table 3, the temperature was determined to be 110 °C for BiPh₂Me. A range of 60-130 °C was determined for all the heteroleptic compounds. For comparison, a temperature of 175 °C was determined for BiPh₃. As to vapor pressure data for BiMe₃, *Fluid Phase Equilibria*, 360, 106-110 (2013) reports the temperature required for 1 Torr of vapor pressure to be < 20°C. The 1 Torr temperature is of interest to atomic layer deposition processes as this value represent the set temperature for the precursor container in order to run the process in a reasonable manner. The precursors of this invention have 1 torr vapor pressure between 30 °C and 130 °C.

[0119] **Example 7: Deposition of Bismuth-Containing Films**

[0120] Several bismuth precursors were tested in deposition experiments in order to deposit Bi₂O₃ thin films. The experiments were performed in a manner consistent with ALD (*i.e.*, the precursor and oxidant were delivered into the reaction chamber independently separated by an inert gas purge). In general, the heteroleptic bismuth precursors required reasonable container temperatures of around 100 °C to deliver a saturating pulse of gaseous precursors. This was expected due to their intermediate volatile properties compared to the homoleptic bismuth precursors. The tri (neo-pentyl) bismuth precursor is volatile and required mild container heating to produce enough vapor pressure. The container temperature for tri(phenyl) bismuth was set high at 160 °C in order to deliver an adequate amount of precursor vapor per pulse. Uniformly heating a precursor container and delivery lines to around 100 °C without cold spots is a manageable task with heating jackets and heating tape commonly used in ALD equipment.

[0121] To determine the precursor stability under the reactor settings, “Bi CVD” experiments were performed. As shown in Table 4, the precursors were pulsed into the reaction chamber (without

the O₃ oxidant) to determine the amount of bismuth deposited due to thermal decomposition. The heteroleptic precursors deposited less than 1 Å of bismuth after 100 pulses at 280 °C and 320 °C. At 400 °C, di(neo-pentyl) phenylbismuth deposited 3 Å of bismuth indicating a small increase in thermal decomposition. Tri (neo-pentyl) bismuth deposited 1542 Å of bismuth at 400 °C, whereas triphenyl bismuth deposited negligible amounts of bismuth at all three temperatures. These results clearly demonstrate a relationship between the number of bismuth-aryl bonds and thermal stability. Additionally, the heteroleptic bismuth precursors exhibited enough thermal stability to allow for controlled deposition of Bi₂O₃ in a manner consistent with ALD. Growth rates for diphenyl methylbismuth and di(neo-pentyl) phenylbismuth were measured to be 0.13 Å/cycle at optimized precursor pulse times near saturation conditions. As shown in FIG. 4, precursor pulse times for diphenyl-methylbismuth and di(neo-pentyl) phenylbismuth were selected to be 5s and 2s for near self-limiting growth behavior, according to saturation curves. Conditions in FIG. 4 are as follows: 280 °C; 100 cycles, 5 s O₃ pulse for BiPh₂Me; 2 s O₃ pulse for BiPh(Np)₂ and BiNp₃. Notably, tri(neo-pentyl) bismuth did not show self-limiting growth, likely due to thermal decomposition of the precursor.

Deposition Parameter		BiPh ₃	BiPh ₂ Me	BiPhNp ₂	BiNp ₃
Container Temperature		160 °C	100 °C	90 °C	85 °C
Bi CVD (Å)	280 °C	0.45	1.19	0.84	1.24
	320 °C	-	-	1.26	1.95
	400 °C	0	1.12	3.05	1542.52
GPC at 280 °C (Å/cycle)		0.38	0.13	0.13	0.16
Precursor Pulse (secs)		20	5	2	2
Ozone Pulse (secs)		5	5	2	2
Reactor Type		CN-1, 8" shower head			
Reactor Purge		1000 sccm, Argon			
Chamber Pressure		2 Torr			
Line Purge		30 sccm, Argon, 43 s			
O ₂ Flow		500 sccm			
O ₃ Pulse		2-5 s pulse at 290 g/Nm ³			
Substrate		ZrO ₂			

Table 4

[0122] Example 8: Self-limited Growth of Bi-containing Films on SLG Oxide Layer

[0123] Self-limited growth (SLG) of bismuth-containing film was demonstrated on aluminum oxide SLG oxide layer. The experiments were performed in a manner consistent with ALD (*i.e.*, the precursor and oxidant were delivered into the reaction chamber independently separated by an inert gas purge). SLG oxide layer was deposited by trimethylaluminum/ozone thermal ALD process at 300 °C. Bismuth oxide film was deposited using BiPh₂Me bismuth precursor at 280 °C using the following ALD sequence: BiPh₂Me/Ar purge/O₃/Ar purge = 5 sec/43 sec/2 sec/43 sec. The number of cycles in bismuth oxide ALD process varied from 20 to 250 to determine if self-limited growth can be achieved. FIG. 5 shows the dependence of bismuth oxide thickness on the number of ALD cycles. The result shows that when aluminum oxide is used as SLG oxide layer self-limited growth of bismuth oxide film it can be accomplished, while no self-limited growth is observed on zirconium oxide.

[0124] It is anticipated that the disclosed and claimed methods could be used in conjunction with deposition tools commonly found at semiconductor manufacturing sites to produce molybdenum-containing layers for logic applications and other potential functions.

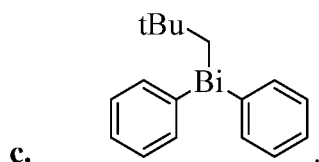
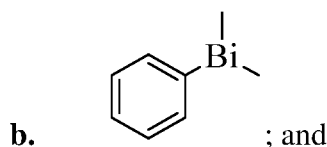
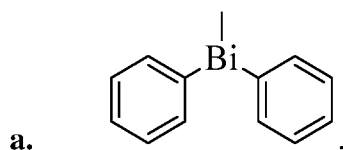
[0125] The foregoing description is intended primarily for purposes of illustration. Although the disclosed and claimed subject matter has been shown and described with respect to an exemplary embodiment thereof, it should be understood by those skilled in the art that the foregoing and various other changes, omissions, and additions in the form and detail thereof may be made therein without departing from the spirit and scope of the disclosed and claimed subject matter.

CLAIMS

What is claimed is:

1. A precursor of the formula $\text{Bi}(\text{R}^a)_x(\text{Ar})_{3-x}$ wherein

- (i) $x = 1$ or 2 ,
- (ii) each R^a is independently one of an unsubstituted linear C_1 - C_6 alkyl group, a linear C_1 - C_6 alkyl group substituted with one or more halogen, a linear C_1 - C_6 alkyl group substituted with an amino group, an unsubstituted branched C_3 - C_6 alkyl group, a branched C_3 - C_6 alkyl group substituted with one or more halogen, a branched C_3 - C_6 alkyl group substituted with an amino group, an unsubstituted amine, a substituted amine, and $-\text{Si}(\text{CH}_3)_3$ and
- (iii) each Ar is independently one of a C_3 - C_8 unsubstituted aromatic group, a C_3 - C_8 aromatic group substituted with one or more halogen, a C_3 - C_8 aromatic group substituted with an amino group, a 5-member heterocyclic ring and 6-member heterocyclic ring; and
- (iv) the precursor does not include:

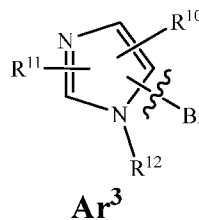
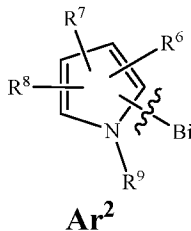
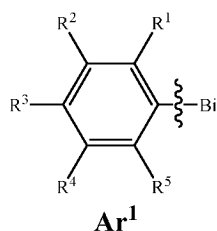


- 2. The precursor of claim 1, wherein R^a comprises an unsubstituted linear C_1 - C_6 alkyl group.
- 3. The precursor of claim 1, wherein R^a comprises a methyl group.
- 4. The precursor of claim 1, wherein R^a comprises an ethyl group.
- 5. The precursor of claim 1, wherein R^a comprises a propyl group.
- 6. The precursor of claim 1, wherein R^a comprise a butyl group.
- 7. The precursor of claim 1, wherein R^a comprises a pentyl group.
- 8. The precursor of claim 1, wherein R^a comprises a hexyl group.

9. The precursor of claim 1, wherein R^a comprises a substituted linear C₁-C₆ alkyl group substituted with one or more halogen.
10. The precursor of claim 1, wherein R^a comprises a methyl group substituted with one or more halogen.
11. The precursor of claim 1, wherein R^a comprises an ethyl group substituted with one or more halogen.
12. The precursor of claim 1, wherein R^a comprises a propyl group substituted with one or more halogen.
13. The precursor of claim 1, wherein R^a comprises a butyl group substituted with one or more halogen.
14. The precursor of claim 1, wherein R^a comprises a pentyl group substituted with one or more halogen.
15. The precursor of claim 1, wherein R^a comprises a hexyl group substituted with one or more halogen.
16. The precursor of any of claims 9-15, wherein the one or more halogen comprises fluorine.
17. The precursor of any of claims 9-15, wherein the one or more halogen comprises chlorine.
18. The precursor of any of claims 9-15, wherein the one or more halogen comprises bromine.
19. The precursor of any of claims 9-15, wherein the one or more halogen comprises iodine.
20. The precursor of claim 1, wherein R^a is a substituted linear C₁-C₆ alkyl group substituted with an amino group.
21. The precursor of claim 1, wherein R^a comprises a methyl group substituted with an amino group.
22. The precursor of claim 1, wherein R^a comprises an ethyl group substituted with an amino group.
23. The precursor of claim 1, wherein R^a comprises a propyl group substituted with an amino group.
24. The precursor of claim 1, wherein R^a comprises a butyl group substituted with an amino group.
25. The precursor of claim 1, wherein R^a comprises a pentyl group substituted with an amino group.
26. The precursor of claim 1, wherein R^a comprises a hexyl group substituted with an amino group.
27. The precursor of claim 1, wherein R^a comprises an unsubstituted branched C₃-C₆ alkyl group.
28. The precursor of claim 1, wherein R^a comprises an iso-propyl group.
29. The precursor of claim 1, wherein R^a comprises an iso-butyl group.
30. The precursor of claim 1, wherein R^a comprises a sec-butyl group.
31. The precursor of claim 1, wherein R^a comprises a tert-butyl group.

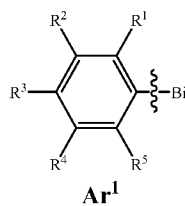
32. The precursor of claim 1, wherein R^a comprises a branched pentyl group.
33. The precursor of claim 1, wherein R^a comprises a neopentyl group.
34. The precursor of claim 1, wherein R^a comprises a branched hexyl group.
35. The precursor of claim 1, wherein R^a comprises a substituted branched C₃-C₆ alkyl group substituted with one or more halogen.
36. The precursor of claim 1, wherein R^a comprises an iso-propyl group substituted with one or more halogen.
37. The precursor of claim 1, wherein R^a comprises an iso-butyl group substituted with one or more halogen.
38. The precursor of claim 1, wherein R^a comprises a sec-butyl group substituted with one or more halogen.
39. The precursor of claim 1, wherein R^a comprises a tert-butyl group substituted with one or more halogen.
40. The precursor of claim 1, wherein R^a comprises a branched pentyl group substituted with one or more halogen.
41. The precursor of claim 1, wherein R^a comprises a neopentyl group substituted with one or more halogen.
42. The precursor of claim 1, wherein R^a comprises a branched hexyl group substituted with one or more halogen.
43. The precursor of any of claim 36-42, wherein the one or more halogen comprises fluorine.
44. The precursor of any of claim 36-42, wherein the one or more halogen comprises chlorine.
45. The precursor of any of claim 36-42, wherein the one or more halogen comprises bromine.
46. The precursor of any of claim 36-42, wherein the one or more halogen comprises iodine.
47. The precursor of claim 1, wherein R^a comprises a substituted branched C₃-C₆ alkyl group substituted with an amino group.
48. The precursor of claim 1, wherein R^a comprises an iso-propyl group substituted with an amino group.
49. The precursor of claim 1, wherein R^a comprises an iso-butyl group substituted with an amino group.
50. The precursor of claim 1, wherein R^a comprises a sec-butyl group substituted with an amino group.

- 51.** The precursor of claim 1, wherein R^a comprises a tert-butyl group substituted with an amino group.
- 52.** The precursor of claim 1, wherein R^a comprises a branched pentyl group substituted with an amino group.
- 53.** The precursor of claim 1, wherein R^a comprises a neopentyl group substituted with an amino group.
- 54.** The precursor of claim 1, wherein R^a comprises a branched hexyl group substituted with an amino group.
- 55.** The precursor of claim 1, wherein R^a comprises an unsubstituted amine.
- 56.** The precursor of claim 1, wherein R^a comprises a substituted amine.
- 57.** The precursor of claim 1, wherein R^a comprises $-\text{Si}(\text{CH}_3)_3$.
- 58.** The precursor of claim 1, wherein R^a comprises one or more of a methyl group, an ethyl group, a propyl group, an n-butyl group, an n-pentyl group, an iso-propyl group, an iso-butyl group, an iso-pentyl group, a sec-butyl group, a sec-pentyl group, a tert-butyl group and a tert-pentyl group.
- 59.** The precursor of claim 1, wherein each Ar independently comprises one of:



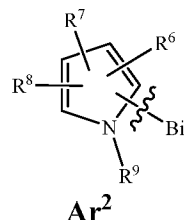
wherein each of R^1 - R^{12} is independently H or R^a , wherein R^a is defined as in claim 1.

- 60.** The precursor of claim 1, wherein each Ar independently comprises:



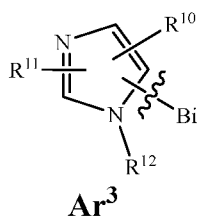
where each of R^1 - R^5 is independently H or R^a , wherein R^a is defined as in claim 1.

61. The precursor of claim 1, wherein each Ar independently comprises:



where each of R⁶-R⁹ is independently H or R^a, wherein R^a is defined as in claim 1.

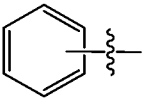
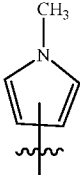
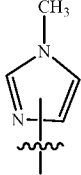
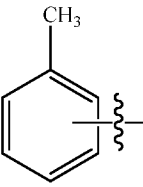
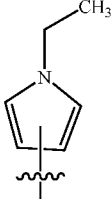
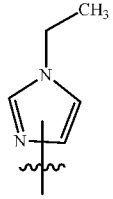
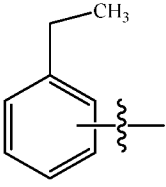
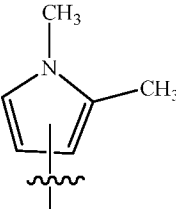
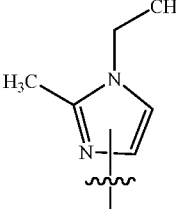
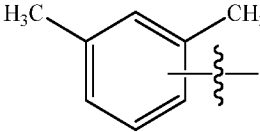
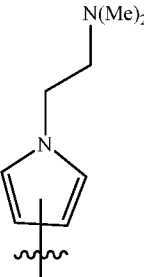
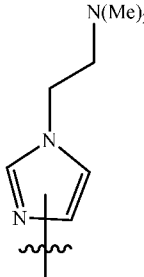
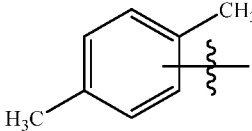
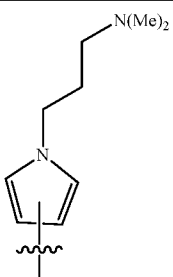
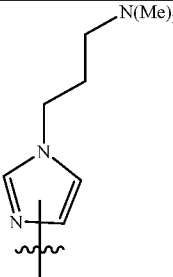
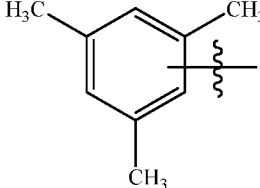
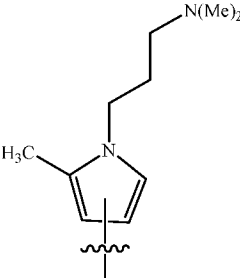
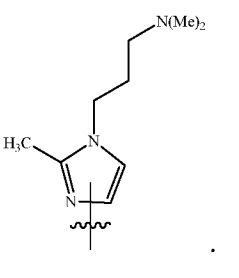
62. The precursor of claim 1, wherein each Ar independently comprises:



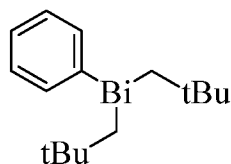
where each of R¹⁰-R¹² is independently H or R^a, wherein R^a is defined as in claim 1.

63. The precursor of any of claims 59-62, wherein each of R¹-R¹² is independently H.
64. The precursor of any of claims 59-62, wherein each of R¹-R¹² is independently R^a.
65. The precursor of any of claims 59-62, wherein each of R¹-R¹² is independently the same R^a.
66. The precursor of any of claims 59-62, wherein each of R¹-R¹² is an unsubstituted linear C₁-C₆ alkyl group.
67. The precursor of any of claims 59-62, wherein each of R¹-R¹² is an unsubstituted branched C₃-C₆ alkyl group.

68. The precursor of claim 1, wherein each Ar independently comprises one of:

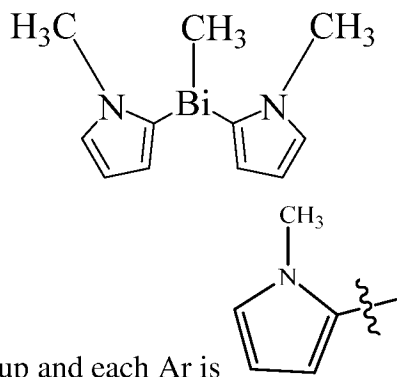
Aryl - Ar ¹	Pyrrolyl - Ar ²	Imidazolyl - Ar ³
		
		
		
		
		
		

69. The precursor of claim 1 having the structure:



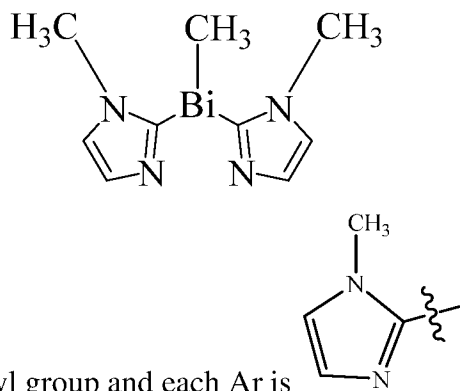
wherein $x = 2$, each R_a is a neo-pentyl group and Ar is a phenyl group.

70. The precursor of claim 1 having the structure:



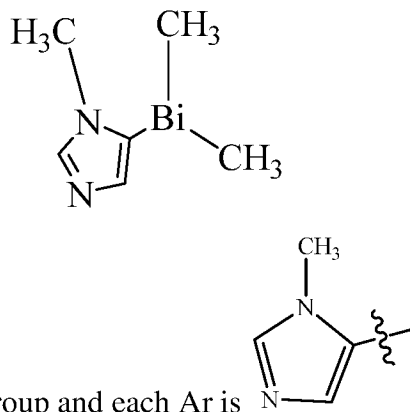
wherein $x = 1$, R_a is a methyl group and each Ar is

71. The precursor of claim 1 having the structure:



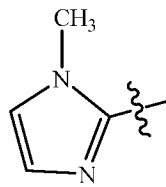
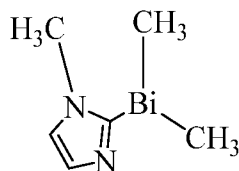
wherein $x = 1$, each R_a is a methyl group and each Ar is

72. The precursor of claim 1 having the structure:



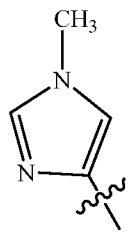
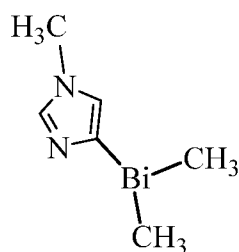
wherein $x = 2$, each R_a is a methyl group and each Ar is

73. The precursor of claim 1 having the structure:



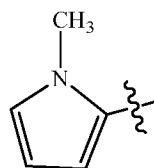
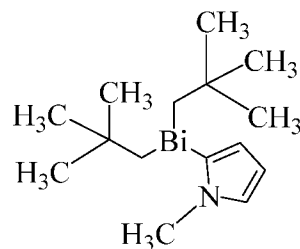
wherein $x = 2$, each R_a is a methyl group and each Ar is

74. The precursor of claim 1 having the structure:



wherein $x = 2$, each R_a is a methyl group and each Ar is

75. The precursor of claim 1 having the structure:



wherein $x = 2$, each R_a is a neo-pentyl group and Ar is

76. A method for forming a bismuth-containing film on at least one surface of a substrate comprising:

- a. providing the substrate with the at least one surface in a reaction vessel;

b. forming a bismuth-containing film on the at least one surface by an atomic layer deposition (ALD) process using one or more heteroleptic bismuth precursor of formula $\text{Bi}(\text{R}^a)_x(\text{Ar})_{3-x}$ wherein

- (i) $x = 1$ or 2 ,
- (ii) each R^a is independently one of an unsubstituted linear C_1 - C_6 alkyl group, a linear C_1 - C_6 alkyl group substituted with one or more halogen, a linear C_1 - C_6 alkyl group substituted with an amino group, an unsubstituted branched C_3 - C_6 alkyl group, a branched C_3 - C_6 alkyl group substituted with one or more halogen, a branched C_3 - C_6 alkyl group substituted with an amino group, an unsubstituted amine, a substituted amine, and $-\text{Si}(\text{CH}_3)_3$ and
- (iii) each Ar is independently one of a C_3 - C_8 unsubstituted aromatic group, a C_3 - C_8 aromatic group substituted with one or more halogen, a C_3 - C_8 aromatic group substituted with an amino group, a 5-member heterocyclic ring and 6-member heterocyclic ring

As a metal source compound for the atomic layer deposition process.

77. The method of claim 76, wherein the heteroleptic bismuth precursor comprises a precursor of any of claims 1-75.

78. The method of claim 76, wherein the heteroleptic bismuth precursor comprises BiPhNp_2 .

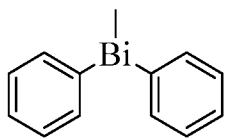
79. The method of claim 76, wherein the heteroleptic bismuth precursor comprises BiPyr_2Me .

80. The method of claim 76, wherein the heteroleptic bismuth precursor comprises BiPyrNp_2 .

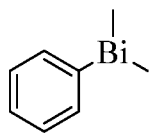
81. The method of claim 76, wherein the heteroleptic bismuth precursor comprises BiImid_2Me .

82. The method of claim 76, wherein the heteroleptic bismuth precursor comprises BiImidMe_2 .

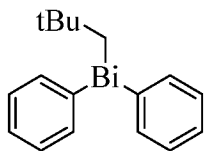
83. The method of claim 76, wherein the heteroleptic bismuth precursor comprises a heteroleptic bismuth precursor of formula $\text{Bi}(\text{R}^a)_x(\text{Ar})_{3-x}$ wherein $x=1$, R^a is a methyl group and each Ar is a phenyl group (“ BiPh_2Me ”):



84. The method of claim 76, wherein the heteroleptic bismuth precursor comprises a heteroleptic bismuth precursor of formula $\text{Bi}(\text{R}^a)_x(\text{Ar})_{3-x}$ wherein $x=2$, each R^a is a methyl group and Ar is a phenyl group (“ BiPhMe_2 ”):



85. The method of claim 76, wherein the heteroleptic bismuth precursor comprises a heteroleptic bismuth precursor of formula $\text{Bi}(\text{R}^a)_x(\text{Ar})_{3-x}$ wherein $x = 1$, R^a is a neo-pentyl group and each Ar is a phenyl group (“ BiPh_2Np ”):



86. The method of claim 76, further comprising introducing into the reaction vessel at least one reactant.

87. The method of claim 76, further comprising introducing into the reaction vessel at least one reactant selected from the group of: water, diatomic oxygen, oxygen plasma, ozone, NO , N_2O , NO_2 , carbon monoxide, carbon dioxide and combinations thereof.

88. The method of claim 76, further comprising introducing into the reaction vessel at least one reactant selected from the group of: ammonia, hydrazine, monoalkylhydrazine, dialkylhydrazine, nitrogen, nitrogen/hydrogen, ammonia plasma, nitrogen plasma, nitrogen/hydrogen plasma, and combinations thereof.

89. The method of claim 76, further comprising introducing into the reaction vessel at least one reactant selected from the group of: hydrogen, hydrogen plasma, a mixture of hydrogen and helium, a mixture of hydrogen and argon, hydrogen/helium plasma, hydrogen/argon plasma, boron-containing compounds, silicon-containing compounds and combinations thereof.

90. A method for forming a bismuth-containing film on at least one surface of a substrate comprising:

- a. providing a substrate in a reaction vessel;
- b. introducing into the reaction vessel one or more heteroleptic bismuth precursor of formula $\text{Bi}(\text{R}^a)_x(\text{Ar})_{3-x}$ wherein
 - (i) $x = 1$ or 2 ,
 - (ii) each R^a is independently one of an unsubstituted linear C_1 - C_6 alkyl group, a linear C_1 - C_6 alkyl group substituted with one or more halogen, a linear C_1 - C_6 alkyl group substituted with an amino group, an unsubstituted branched C_3 - C_6 alkyl

group, a branched C₃-C₆ alkyl group substituted with one or more halogen, a branched C₃-C₆ alkyl group substituted with an amino group, an unsubstituted amine, a substituted amine, and -Si(CH₃)₃ and

(iii) each Ar is independently one of a C₃-C₈ unsubstituted aromatic group, a C₃-C₈ aromatic group substituted with one or more halogen, a C₃-C₈ aromatic group substituted with an amino group, a 5-member heterocyclic ring and 6-member heterocyclic ring;

c. purging the reaction vessel with a first purge gas;

d. introducing into the reaction vessel a source gas;

e. purging the reaction vessel with a second purge gas;

f. sequentially repeating steps b through e until a desired thickness of the bismuth-containing film is obtained.

91. The method of claim 90, wherein the heteroleptic bismuth precursor comprises a precursor of any of claims 1-75.

92. The method of claim 90, wherein the heteroleptic bismuth precursor comprises BiPhNp₂.

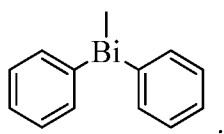
93. The method of claim 90, wherein the heteroleptic bismuth precursor comprises BiPyr₂Me.

94. The method of claim 90, wherein the heteroleptic bismuth precursor comprises BiPyrNp₂.

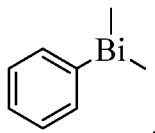
95. The method of claim 90, wherein the heteroleptic bismuth precursor comprises BiImid₂Me.

96. The method of claim 90, wherein the heteroleptic bismuth precursor comprises BiImidMe₂.

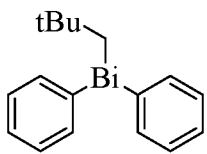
97. The method of claim 90, wherein the heteroleptic bismuth precursor comprises a heteroleptic bismuth precursor of formula Bi(R^a)_x(Ar)_{3-x} wherein x=1, R^a is a methyl group and each Ar is a phenyl group ("BiPh₂Me"):



98. The method of claim 90, wherein the heteroleptic bismuth precursor comprises a heteroleptic bismuth precursor of formula Bi(R^a)_x(Ar)_{3-x} wherein x=2, each R^a is a methyl group and Ar is a phenyl group ("BiPhMe₂"):



99. The method of claim 90, wherein the heteroleptic bismuth precursor comprises a heteroleptic bismuth precursor of formula $\text{Bi}(\text{R}^a)_x(\text{Ar})_{3-x}$ wherein $x = 1$, R^a is a neo-pentyl group and each Ar is a phenyl group (“BiPh₂Np”):



100. The method of claim 90, wherein the source gas is one or more of an oxygen-containing source gas selected from water, diatomic oxygen, oxygen plasma, ozone, NO, N₂O, NO₂, carbon monoxide, carbon dioxide and combinations thereof.

101. The method of claim 90, wherein the source gas is one or more of a nitrogen-containing source gas selected from ammonia, hydrazine, monoalkylhydrazine, dialkylhydrazine, nitrogen, nitrogen/hydrogen, ammonia plasma, nitrogen plasma, nitrogen/hydrogen plasma and mixture thereof.

102. The method of claim 90, wherein the first and second purge gases are each independently selected one or more of argon, nitrogen, helium, neon, and combinations thereof.

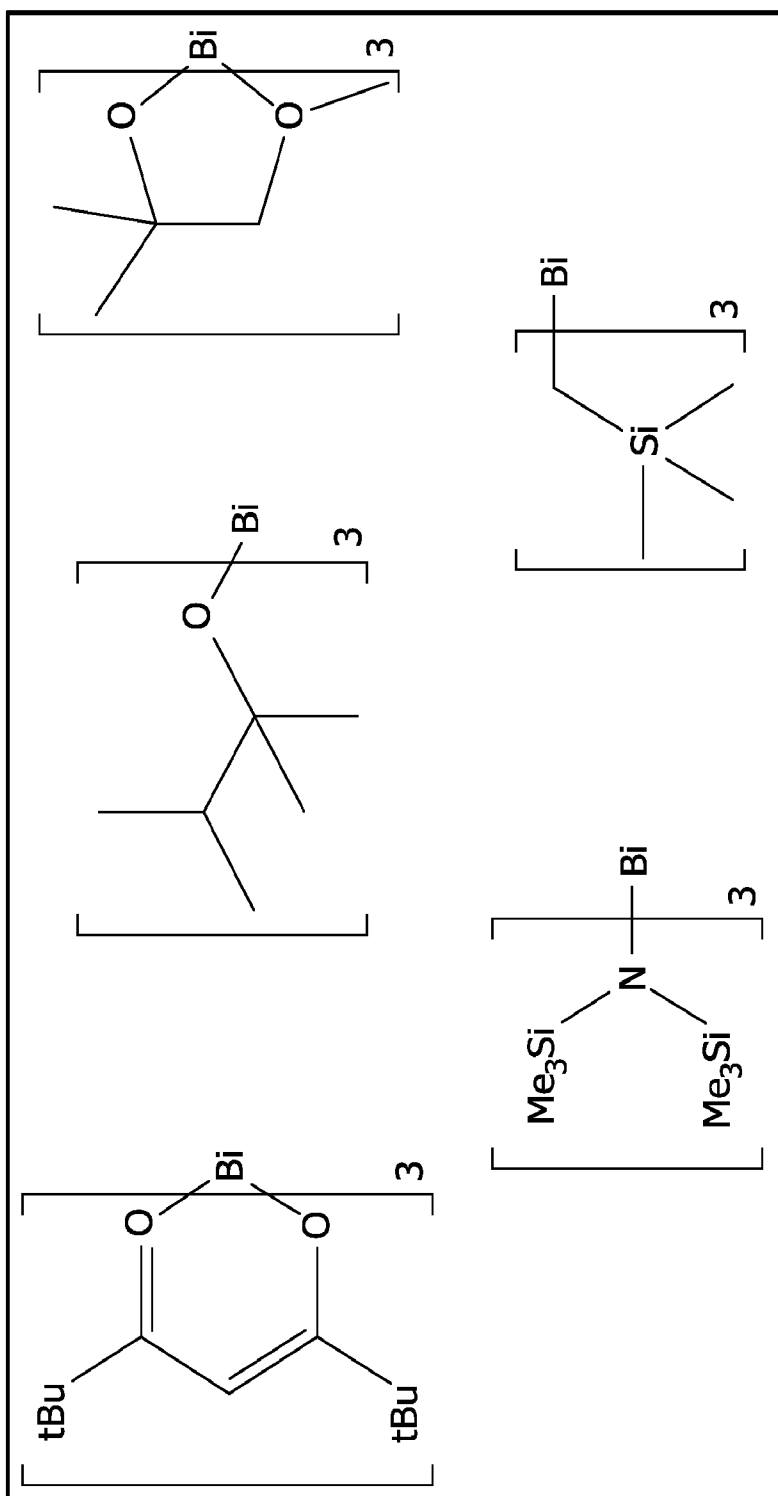
103. The method of claim 90 further comprising applying energy to the heteroleptic bismuth precursor, the source gas, the substrate, and combinations thereof, wherein the energy is one or more of thermal, plasma, pulsed plasma, helicon plasma, high density plasma, inductively coupled plasma, X-ray, e-beam, photon, remote plasma methods and combinations thereof.

104. The method of claim 90, wherein the step b further comprises introducing into the reaction vessel the heteroleptic bismuth precursor using a stream of carrier gas to deliver a vapor of the heteroleptic bismuth precursor into the reaction vessel.

105. The method of claim 90, wherein step b further comprises use of a solvent medium comprising one or more of toluene, mesitylene, isopropylbenzene, 4-isopropyl toluene, 1,3-diisopropylbenzene, octane, dodecane, 1,2,4-trimethylcyclohexane, n-butylcyclohexane, and decahydronaphthalene and combinations thereof.

106. The method of any of claims 76-105, wherein the deposition produces a film exhibiting self-limited growth.

107. A precursor supply package, comprising a vessel and the precursor of any of claims 1-75, wherein the vessel is adapted to contain and dispense the precursor.



Conventional Art

FIG. 1

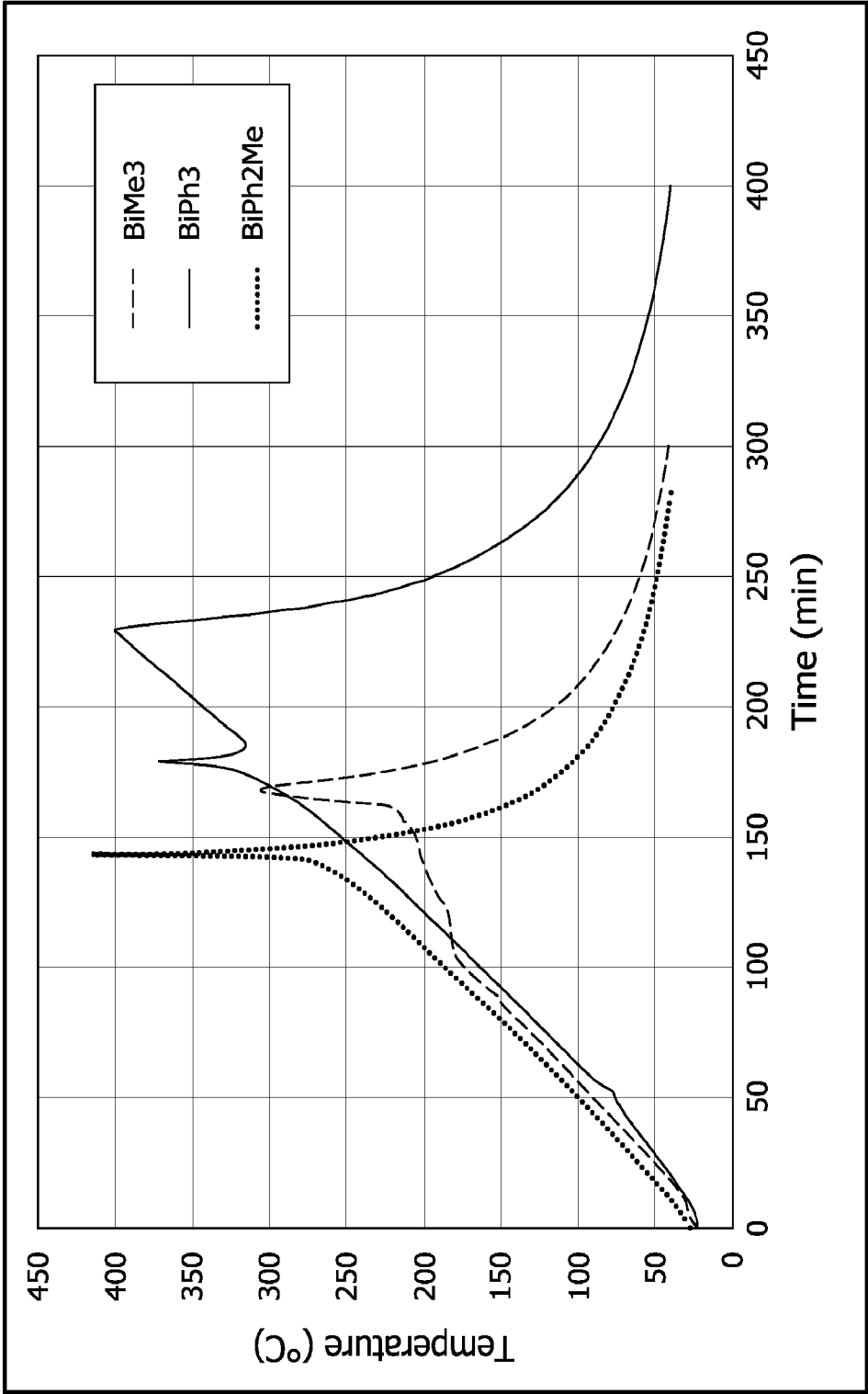


FIG. 2

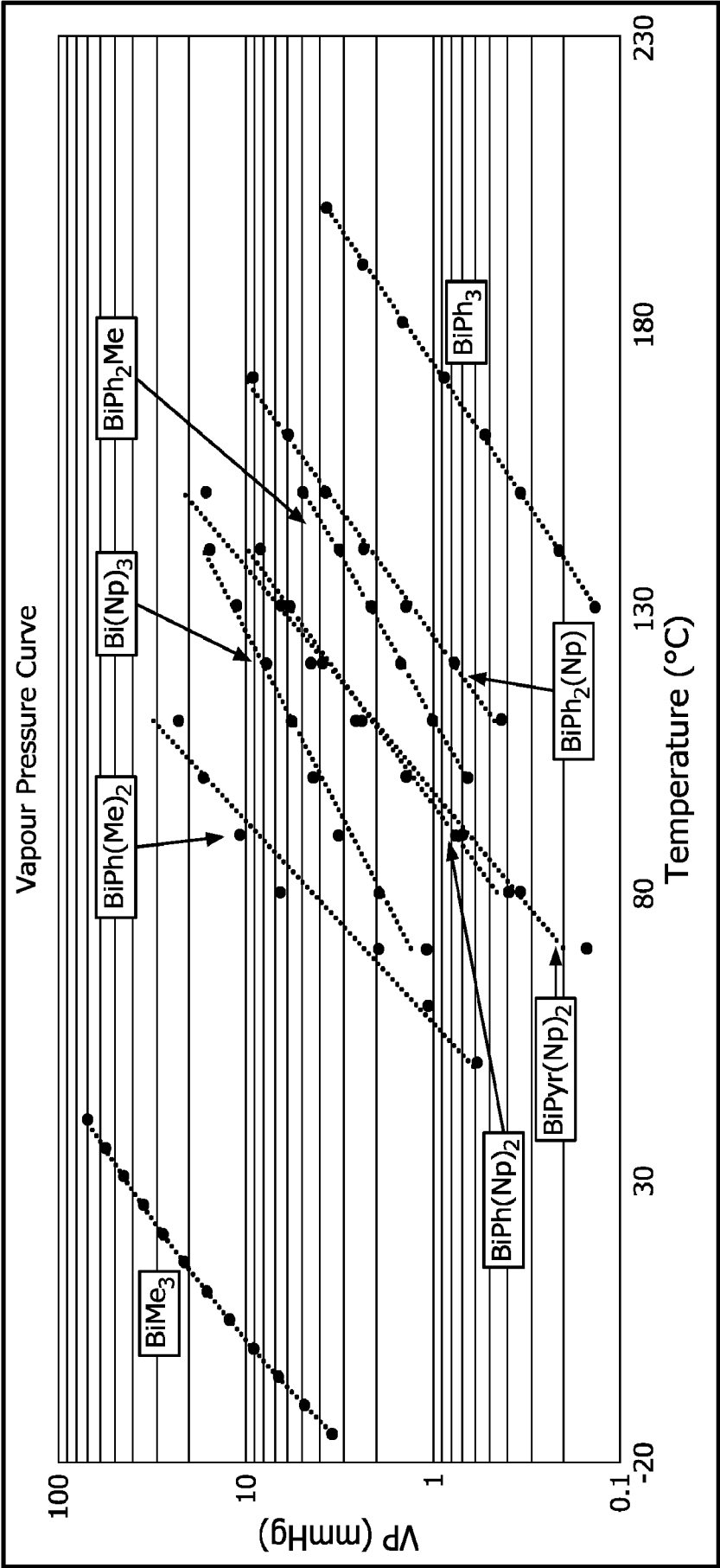


FIG. 3

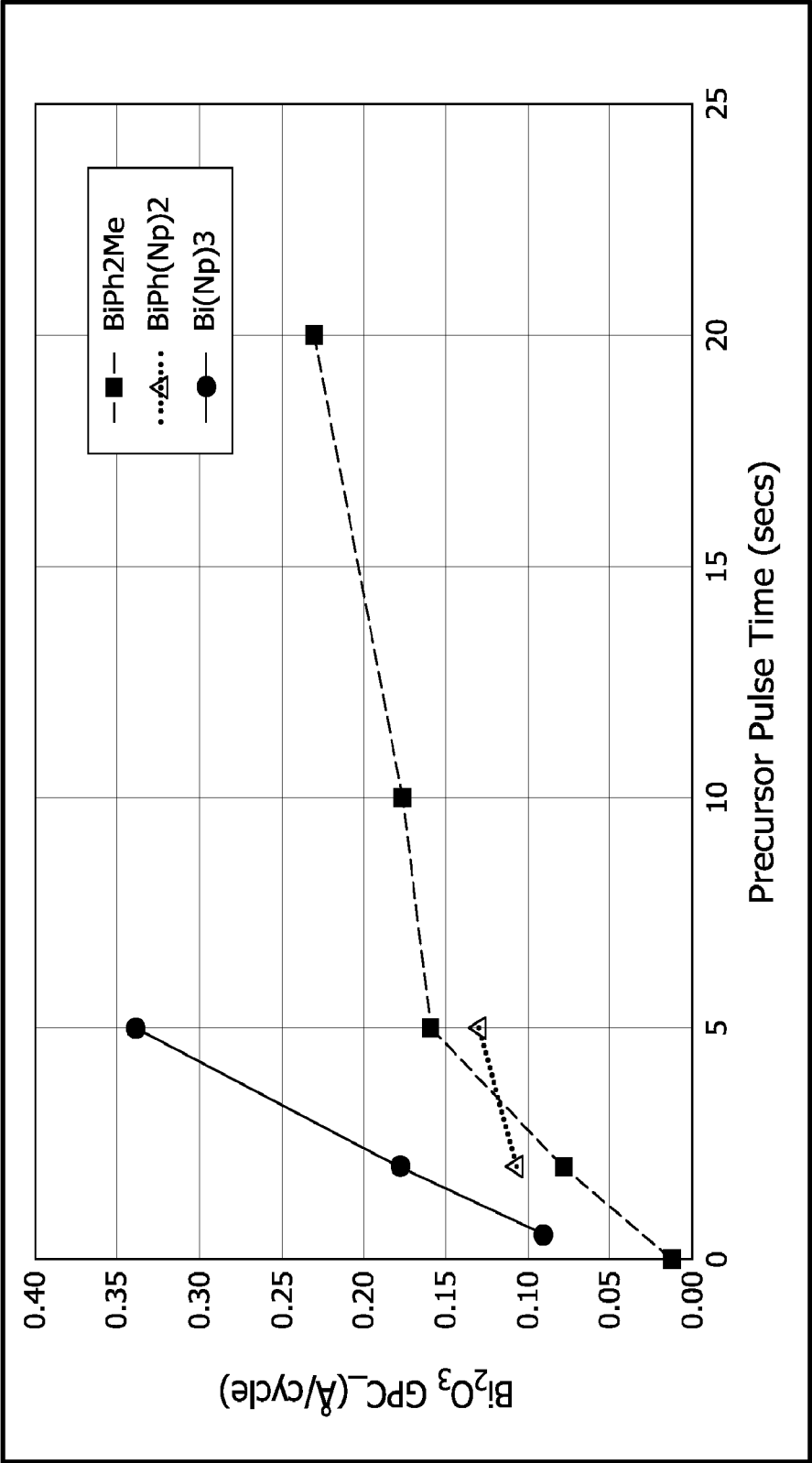


FIG. 4

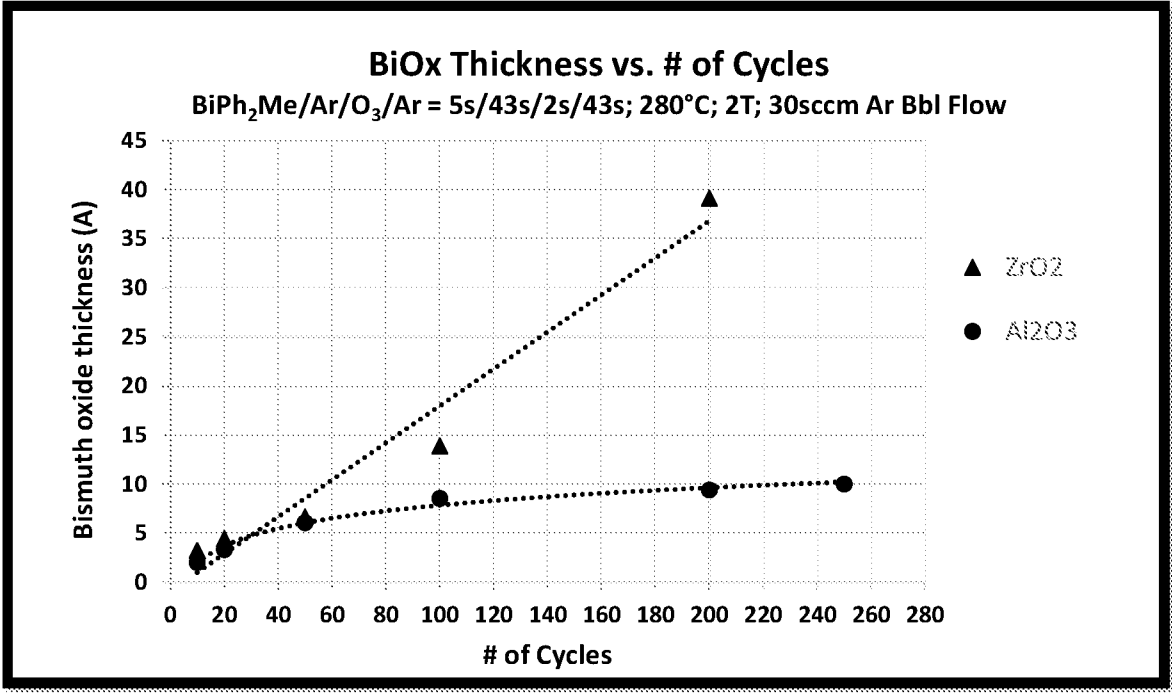


FIG. 5

INTERNATIONAL SEARCH REPORT

International application No
PCT/US2022/081630

A. CLASSIFICATION OF SUBJECT MATTER INV. C07F9/94 C23C16/18 C23C16/40 ADD.		
According to International Patent Classification (IPC) or to both national classification and IPC		
B. FIELDS SEARCHED Minimum documentation searched (classification system followed by classification symbols) C23C C07F		
Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched		
Electronic data base consulted during the international search (name of data base and, where practicable, search terms used) EPO-Internal, CHEM ABS Data		
C. DOCUMENTS CONSIDERED TO BE RELEVANT		
Category*	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	US 2004/204483 A1 (FURUKAWA TAISHI [JP] ET AL) 14 October 2004 (2004-10-14) page 9; example 1 -----	1-107
X	AU 2021 103 847 A4 (AMETA KESHAV LALIT [IN]; KANT RAVI [IN]) 9 September 2021 (2021-09-09) figure 1 -----	1, 59, 60, 64, 65, 107
X	EP 3 292 876 A1 (UNIV GRAZ TECH [AT]) 14 March 2018 (2018-03-14) compound 3 page 13 ----- --/--	1, 28, 59, 60, 63, 107
☒ Further documents are listed in the continuation of Box C. ☒ See patent family annex.		
* Special categories of cited documents : "A" document defining the general state of the art which is not considered to be of particular relevance "E" earlier application or patent but published on or after the international filing date "L" document which may throw doubts on priority claim(s) or which is cited to establish the publication date of another citation or other special reason (as specified) "O" document referring to an oral disclosure, use, exhibition or other means "P" document published prior to the international filing date but later than the priority date claimed "T" later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention "X" document of particular relevance;; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone "Y" document of particular relevance;; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art "&" document member of the same patent family		
Date of the actual completion of the international search		Date of mailing of the international search report
8 March 2023		17/03/2023
Name and mailing address of the ISA/ European Patent Office, P.B. 5818 Patentlaan 2 NL - 2280 HV Rijswijk Tel. (+31-70) 340-2040, Fax: (+31-70) 340-3016		Authorized officer Bourghida, E

INTERNATIONAL SEARCH REPORT

International application No

PCT/US2022/081630

C(Continuation). DOCUMENTS CONSIDERED TO BE RELEVANT		
Category*	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	WO 2017/050425 A1 (MERCK PATENT GMBH [DE]) 30 March 2017 (2017-03-30) example 4 page 21, example 2 page 17 -----	1, 9, 11, 16, 59, 60, 63, 107
X	KIRIJ N V ET AL: "Synthesis and characterization of aryl(trifluoromethyl)bismuth compounds (R-C⁶H⁴)³-nBi(CF³)ⁿ [R=H, 4-CH³, 4-CF³, 3-F, 4-F; n=1 and 2] and the reactions of (C⁶H⁵)³-nBi(CF³)ⁿ [n=0-3] with benzoylpyridinium chloride", JOURNAL OF FLUORINE CHEMISTRY, ELSEVIER, NL, vol. 69, no. 3, 1 December 1994 (1994-12-01), pages 219-223, XP026635699, ISSN: 0022-1139 [retrieved on 1994-12-01] table 2 page 221 -----	1, 9, 10, 16, 59, 60, 64, 65, 107
X	KAUFFMANN THOMAS ET AL: "Neue Reagenzien, XXXII. Alkyldiphenylbismutane: Synthese, Eigenschaften und Halogenolyse", CHEMISCHE BERICHTE, vol. 118, no. 3, 1 March 1985 (1985-03-01) , pages 1031-1038, XP093029552, DE ISSN: 0009-2940, DOI: 10.1002/cber.19851180319 Retrieved from the Internet: URL:https://onlinelibrary.wiley.com/doi/pdf/10.1002/cber.19851180319> page 1032 compounds b-f -----	1, 3-8, 59, 60, 63, 107

INTERNATIONAL SEARCH REPORT

Information on patent family members

International application No

PCT/US2022/081630

Patent document cited in search report	Publication date	Patent family member(s)	Publication date
US 2004204483 A1	14-10-2004	CN 1539841 A	27-10-2004
		DE 602004006904 T2	14-02-2008
		EP 1466918 A1	13-10-2004
		KR 20040087881 A	15-10-2004
		TW I272275 B	01-02-2007
		US 2004204483 A1	14-10-2004

AU 2021103847 A4	09-09-2021	NONE	

EP 3292876 A1	14-03-2018	NONE	

WO 2017050425 A1	30-03-2017	DE 102016001494 A1	23-03-2017
		EP 3352901 A1	01-08-2018
		JP 6824255 B2	03-02-2021
		JP 2018535817 A	06-12-2018
		US 2018272325 A1	27-09-2018
		WO 2017050425 A1	30-03-2017
